

# ESE370: Circuit-Level Modeling, Design, and Optimization for Digital Systems

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Lec 9: September 24, 2021

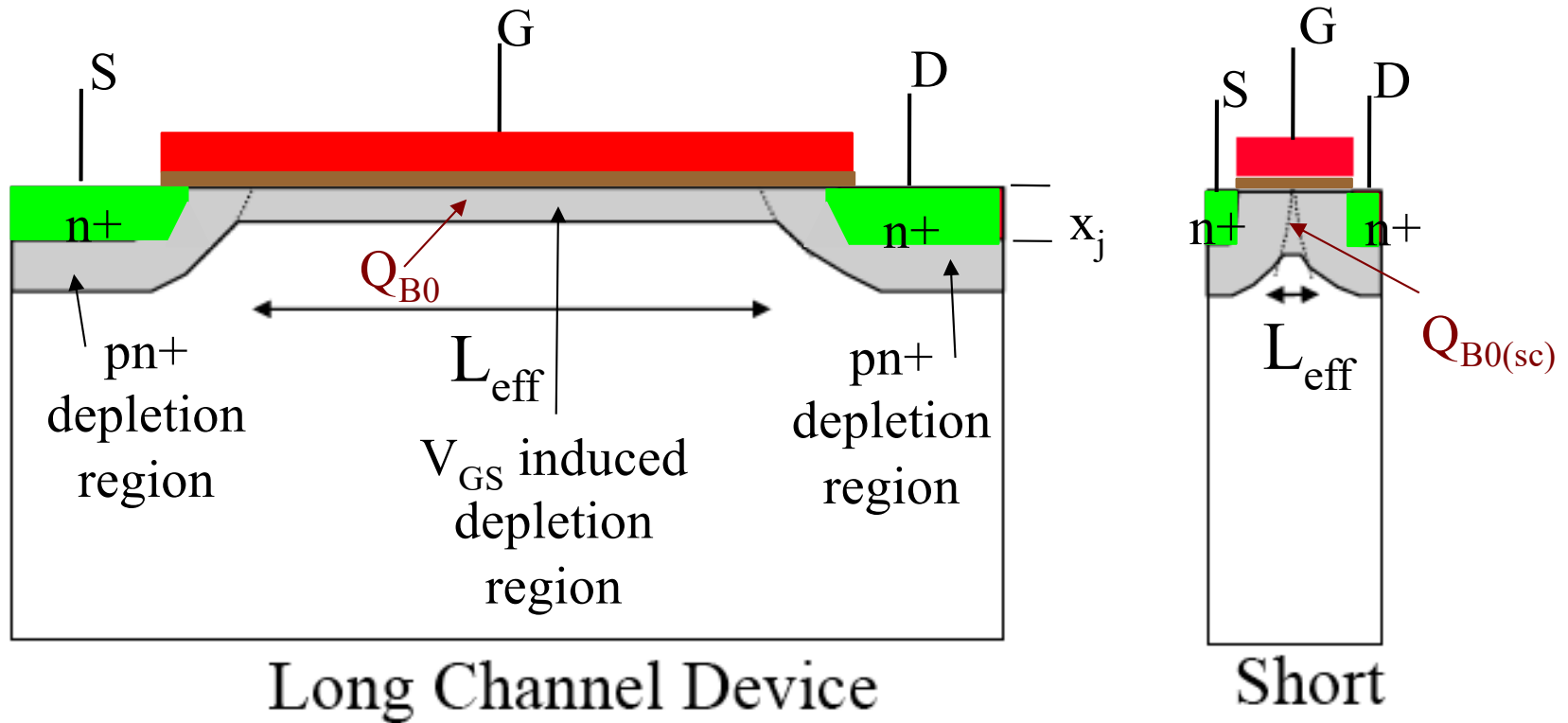
MOS Transistor Details

Capacitance

# Threshold

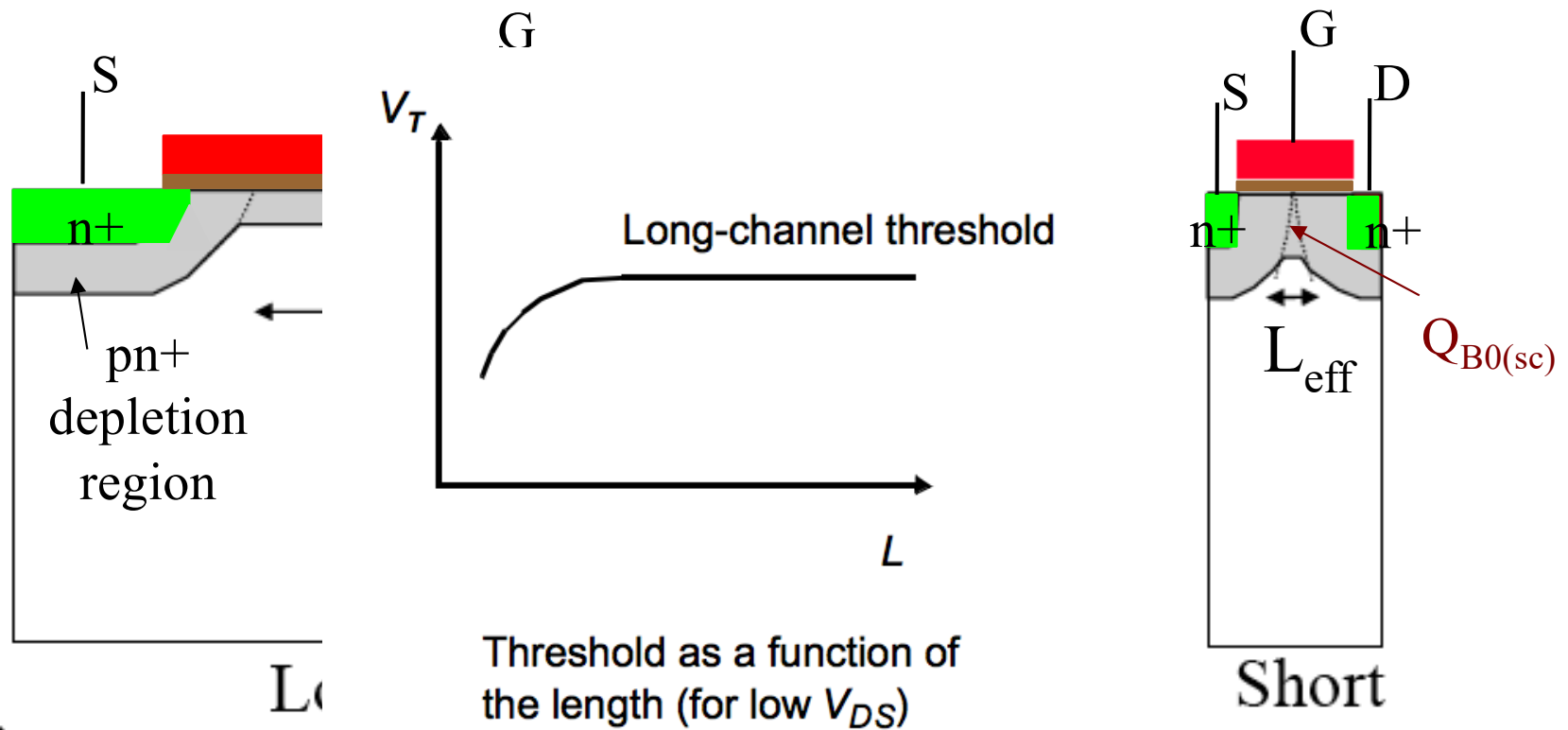
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# Short Channel Effects – $V_T$ Reduction



$$V_{T0} \text{ (short channel)} = V_{T0} - \Delta V_{T0}$$

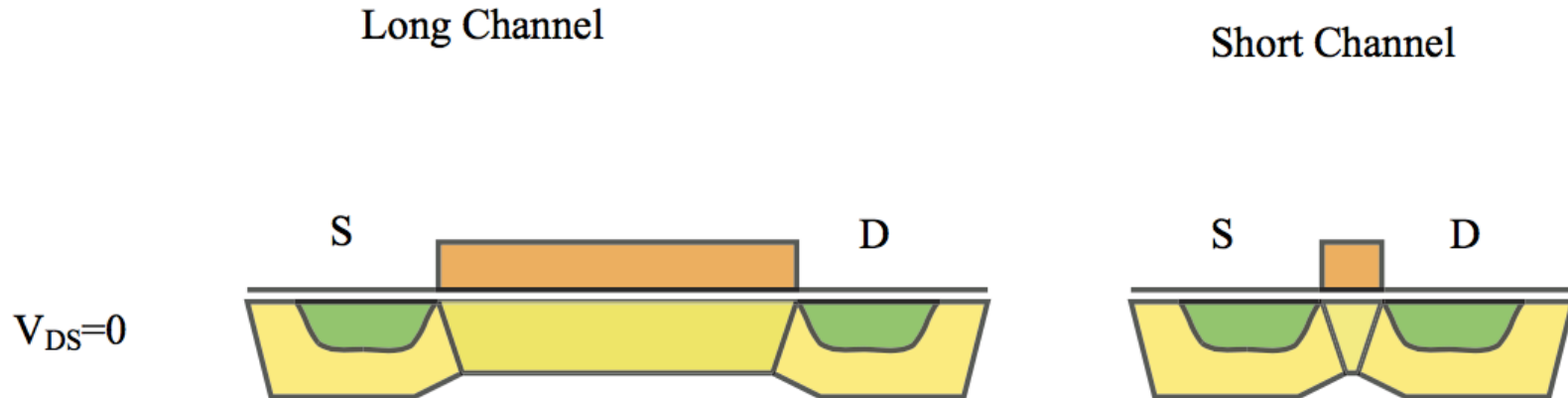
# Short Channel Effects – $V_T$ Reduction



$$V_{T0} (\text{short channel}) = V_{T0} - \Delta V_{T0}$$

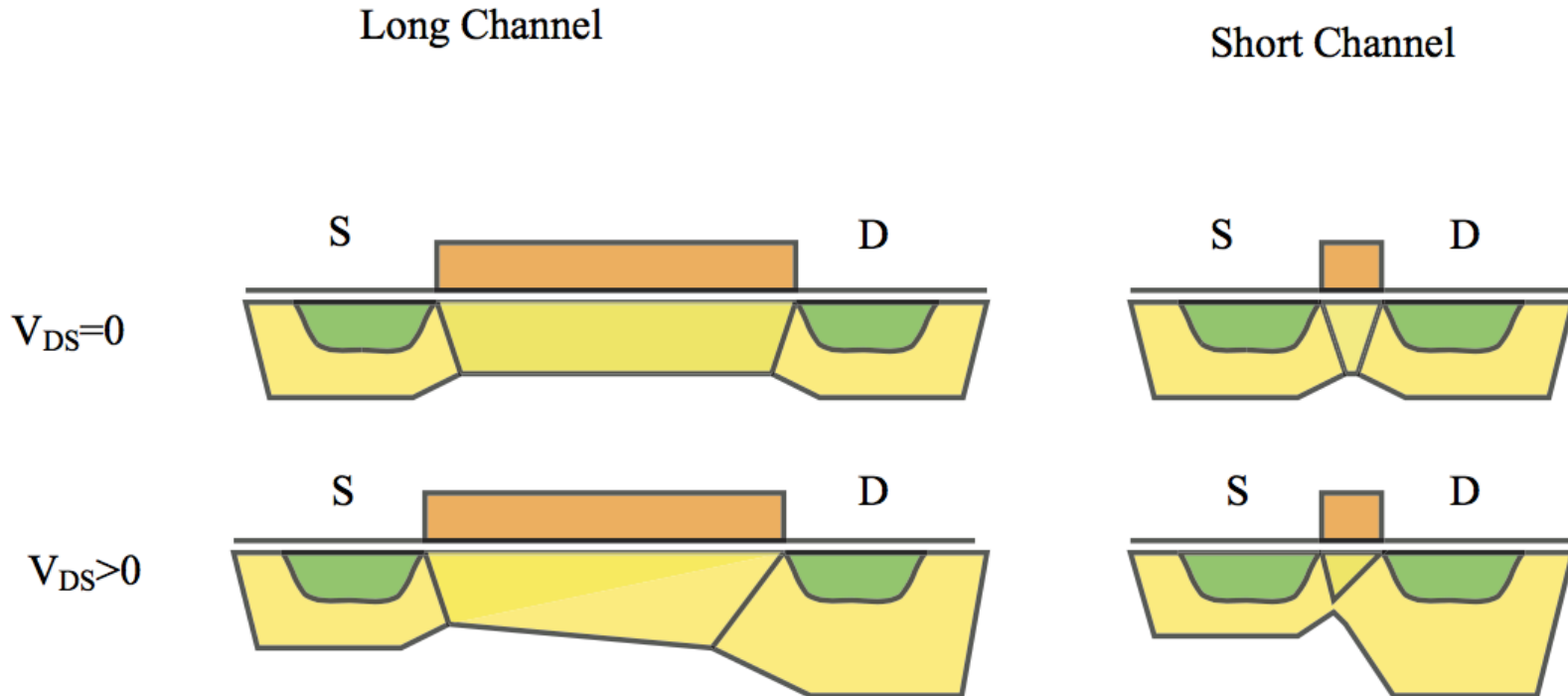
# Short Channel Effects - DIBL

- Drain Induced Barrier Lowering
  - $V_T$  Reduction with Drain Bias



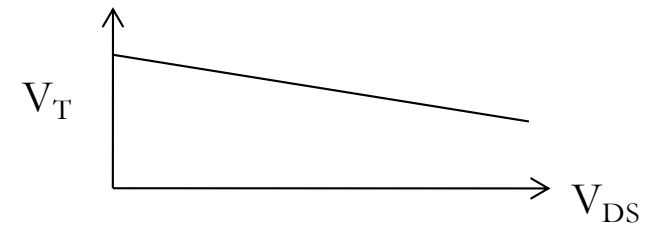
# Short Channel Effects - DIBL

- Drain Induced Barrier Lowering
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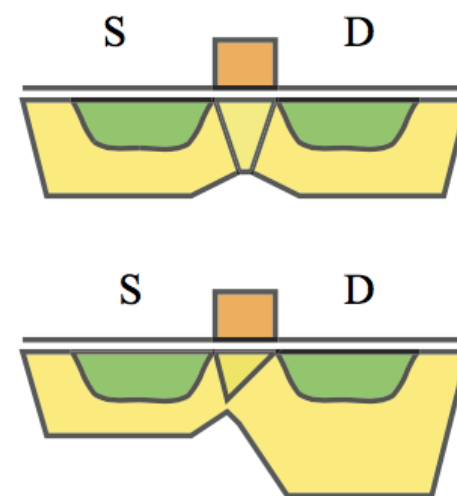
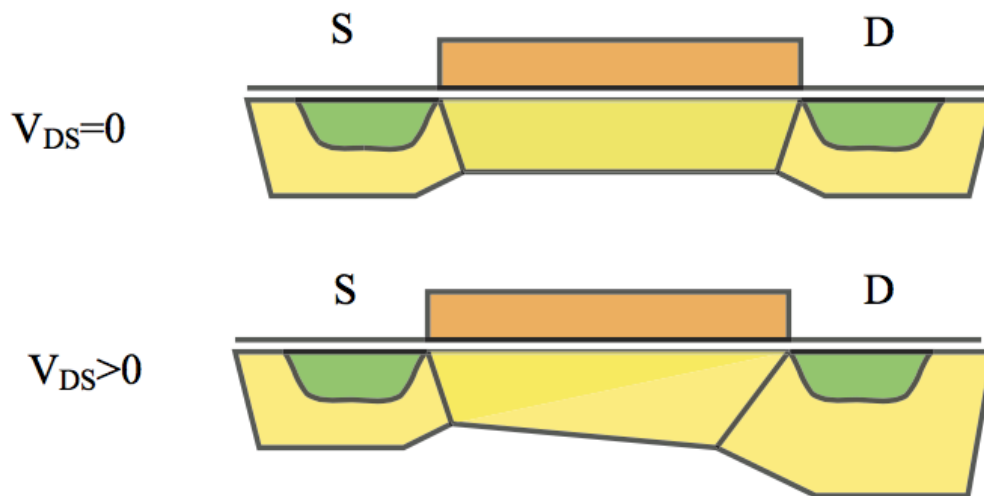
# Short Channel Effects - DIBL

- Drain Induced Barrier Lowering
  - $V_T$  Reduction with Drain Bias



Long Channel

Short Channel



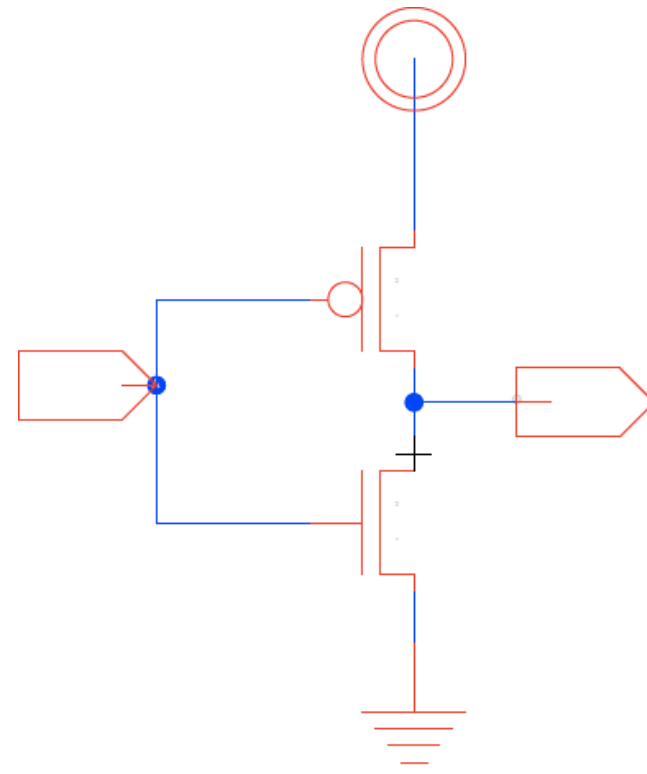
# Threshold Reduction Impact

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# In a Gate?

- What does it impact most?
  - Which device, has large  $V_{ds}$ ?
  - How does this effect operation?
    - Speed of switching?
    - Leakage?

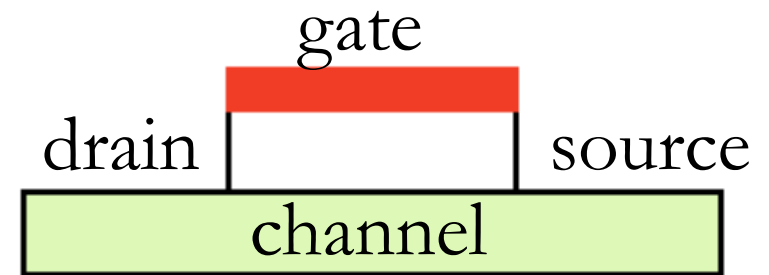
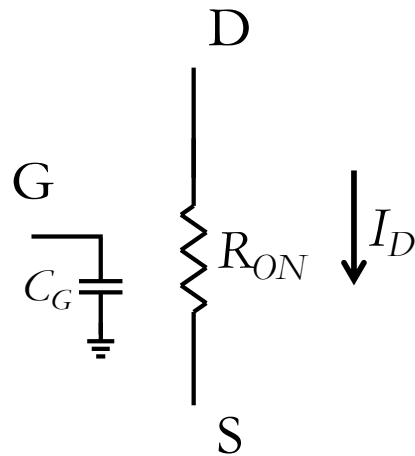


# Simplified Design Flow

- Design a circuit to perform a function with specified minimum speed and optimized power (minimized with an upper bound)
  - Zero order model to design topology
  - First order model to meet speed spec **today**
    - Rise/fall times, propagation delay, gate capacitance, output stage equivalent resistance
  - Transistor IV curves
    - Iterative SPICE simulation – tweak knobs to optimize for power (switching (dynamic), leakage (static), etc.)

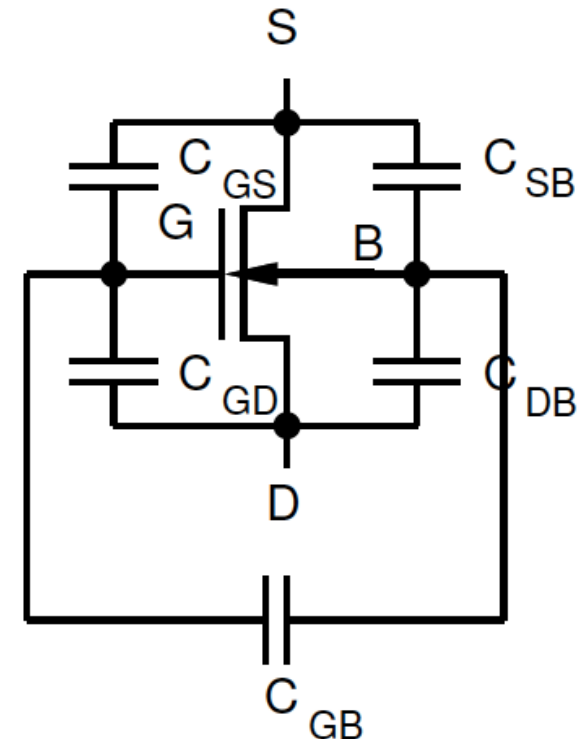
# Capacitance

- First order: gate input looks like a capacitor



- Today:

- Capacitance is not constant
- Capacitance not physically to gnd
  - Modeled as such

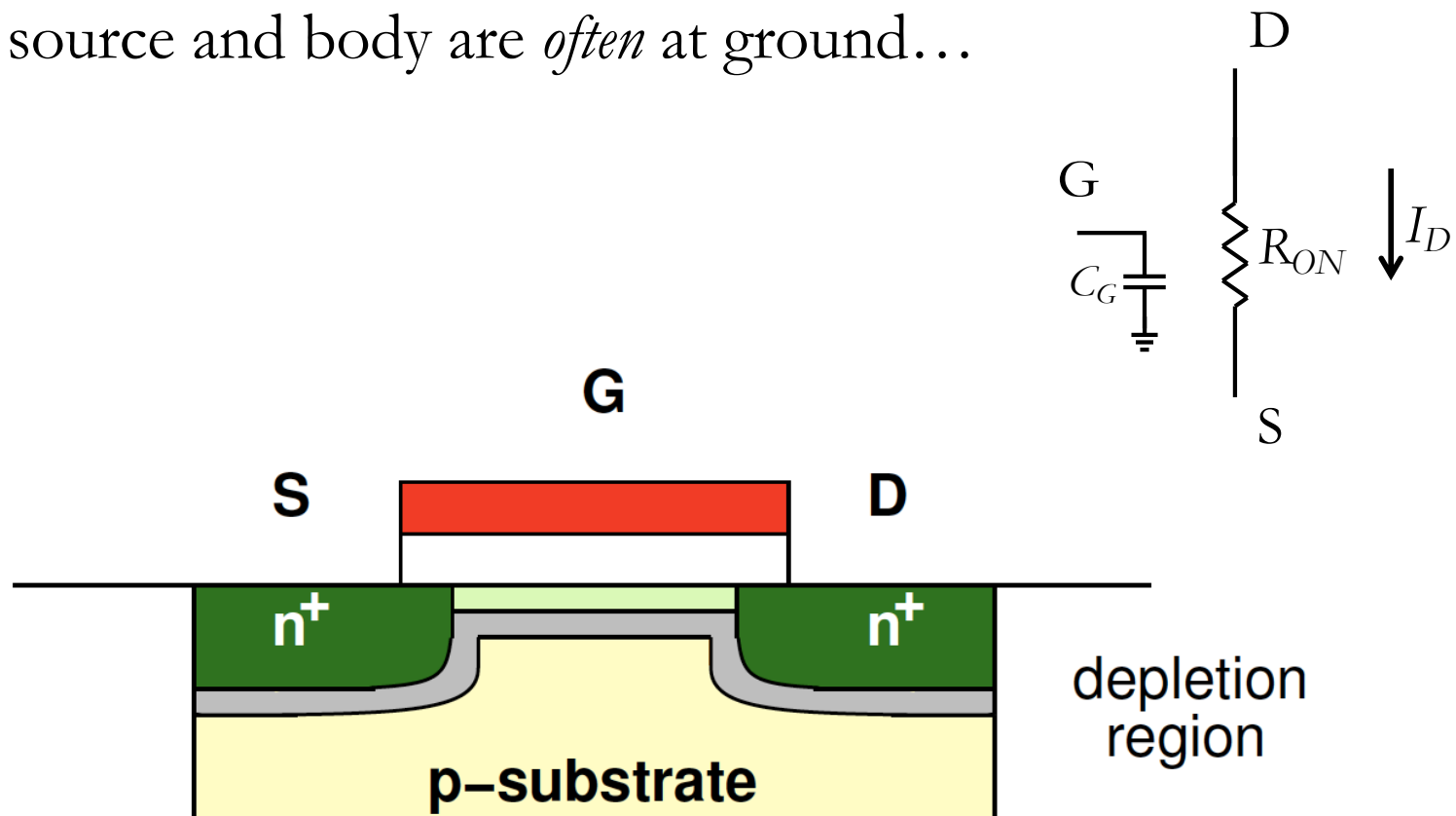


# Capacitance Setup

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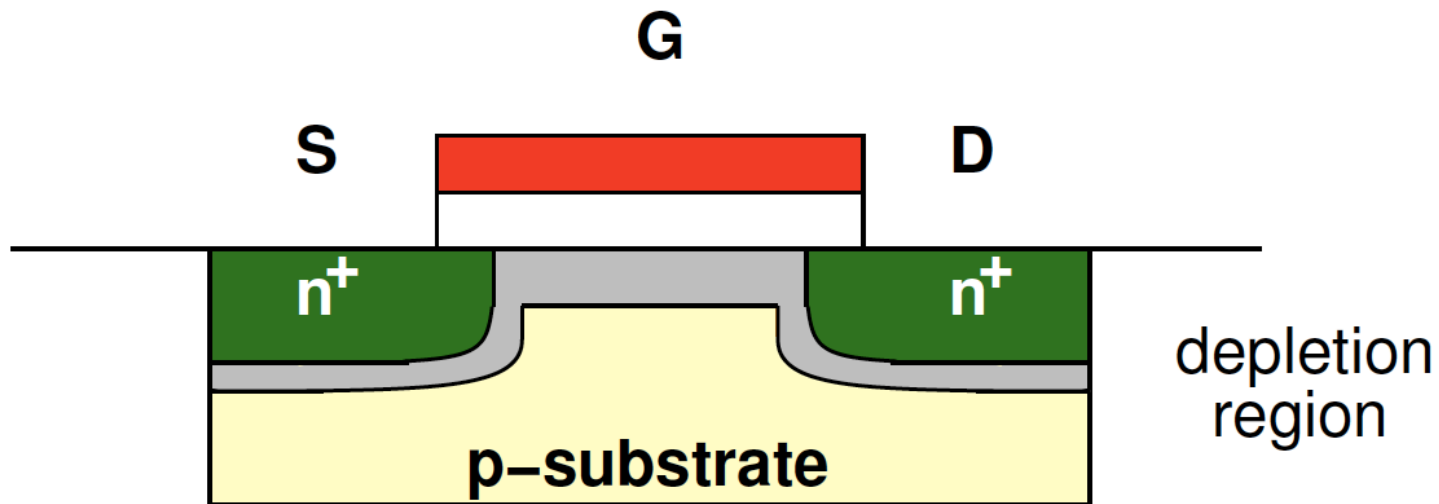
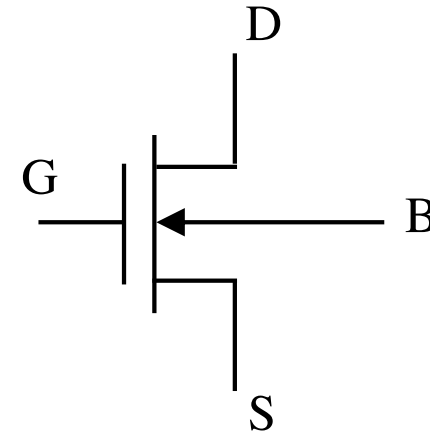
# Capacitance

- ❑ Modeled gate with a capacitor to ground
- ❑ ...but ground isn't really one of our terminals
  - Don't connect directly to it
  - ...source and body are *often* at ground...



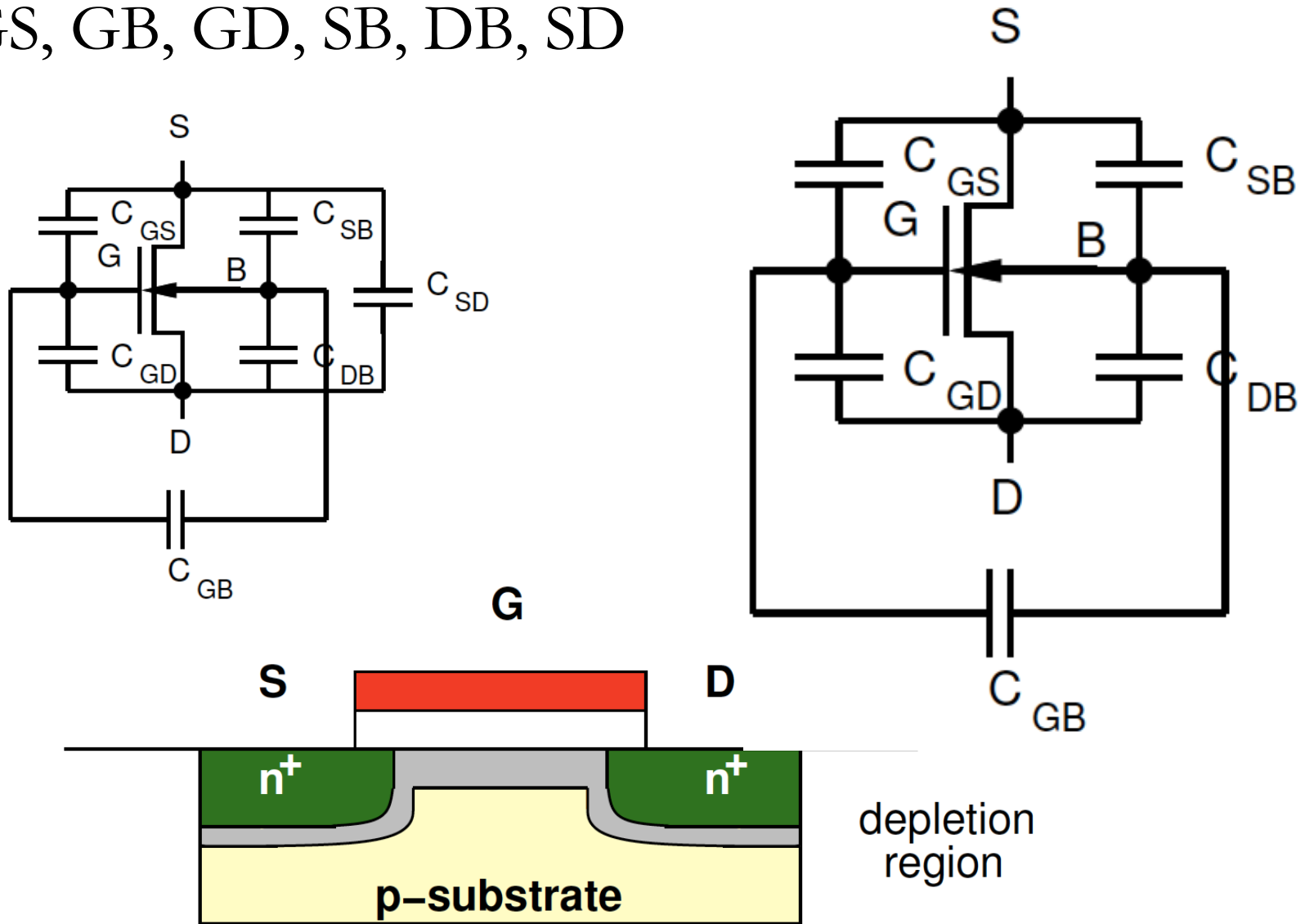
# Capacitance (Preclass 1)

- ❑ Four Terminals
- ❑ How many combinations?
  - 4 things taken 2 at a time?



# Capacitances

- GS, GB, GD, SB, DB, SD

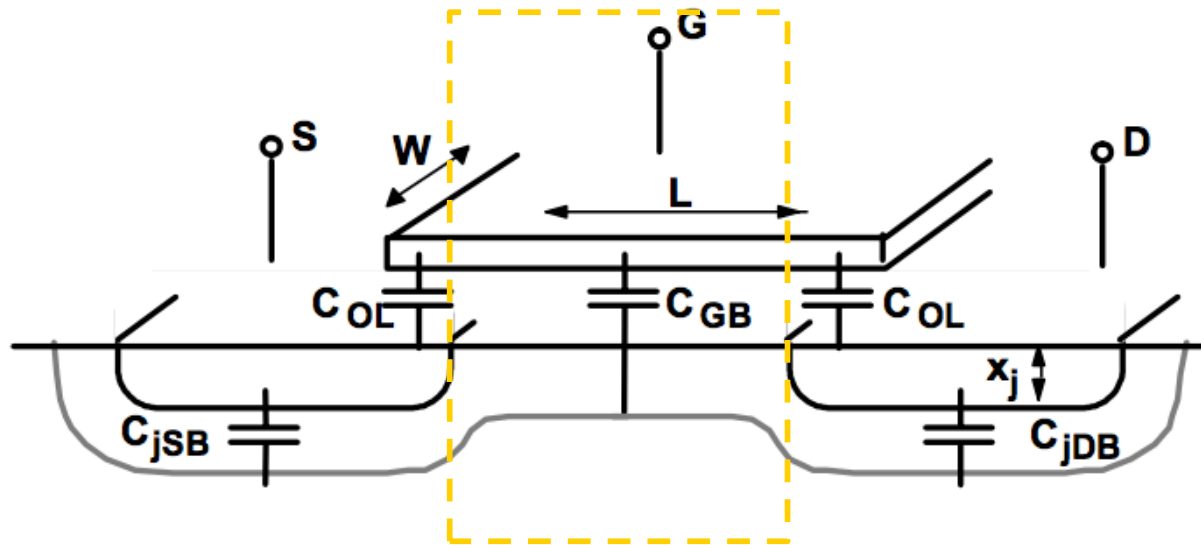


# Capacitance Decomposition

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# MOSFET Parasitic Capacitance



- Any two conductors separated by an insulator form a parallel-plate capacitor
- Two types
  - **Extrinsic** – Outside the box (e.g. junction, overlap)
  - **Intrinsic** – Inside the box (e.g. gate-to-channel)

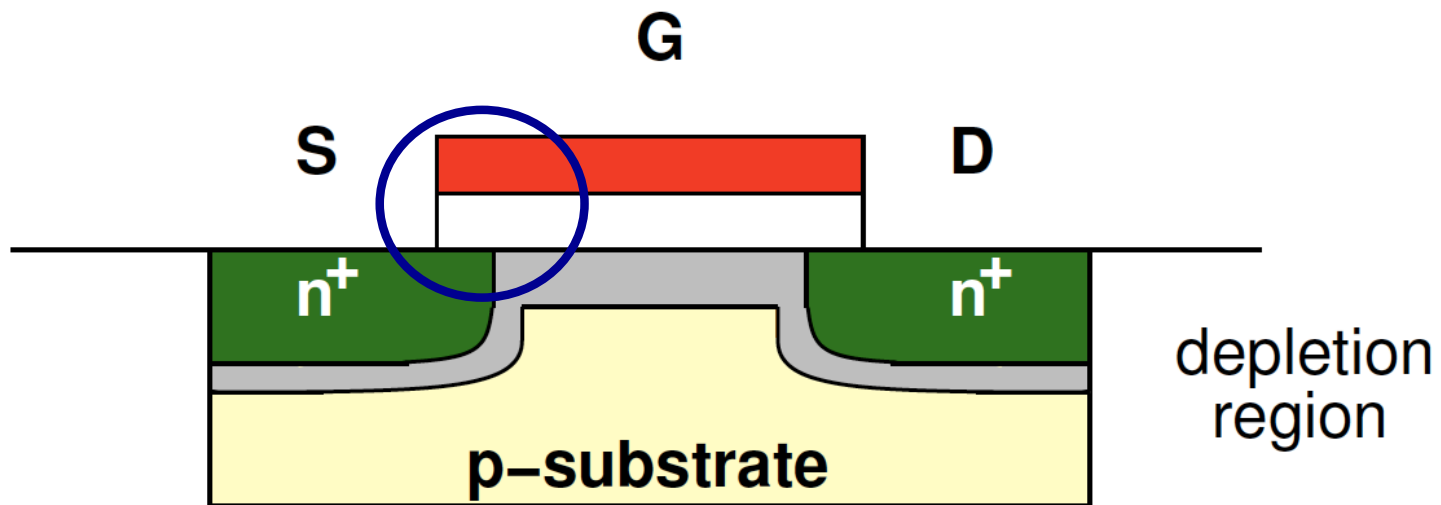
# Overlap Capacitance

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# Overlap

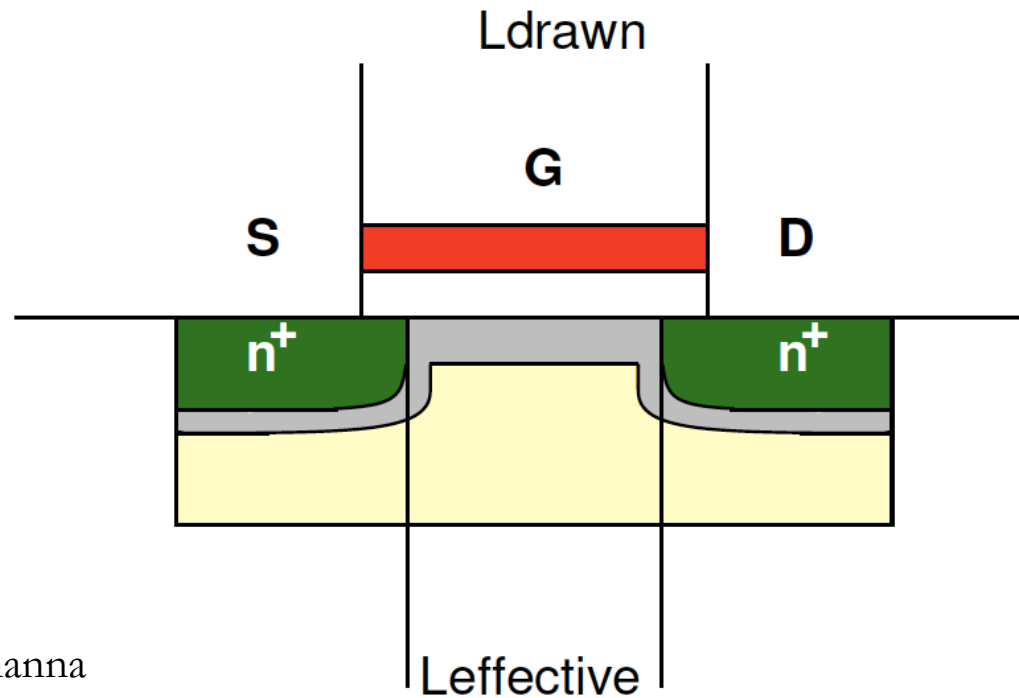
- What is the capacitive implication of gate/source and gate/drain overlap?



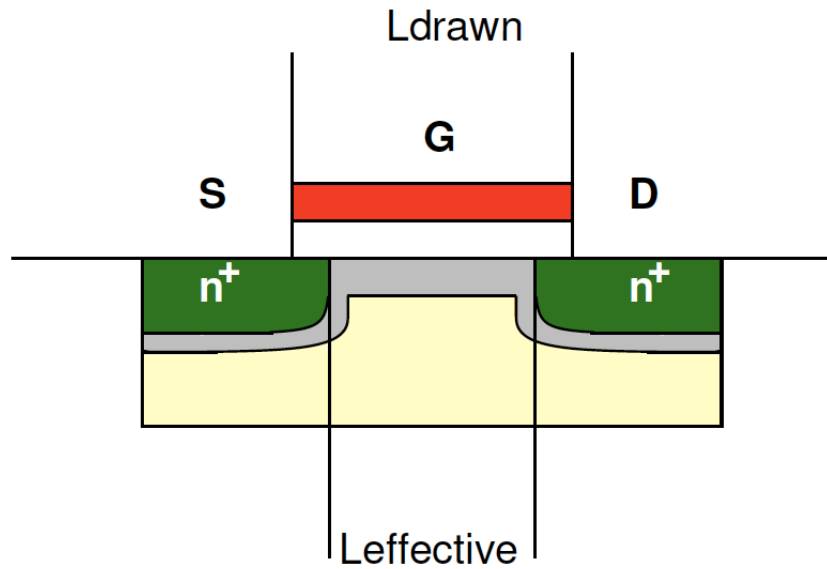


# Overlap

- Length of overlap?



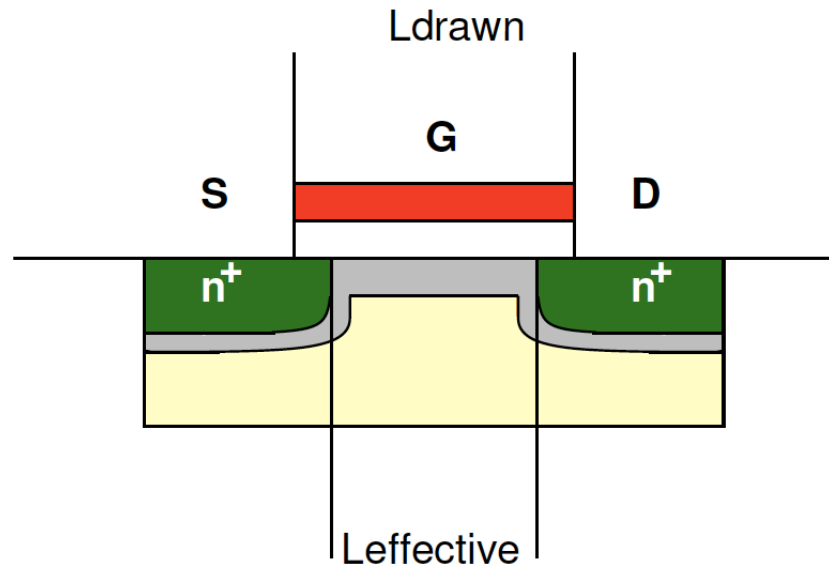
# Overlap Capacitance



$$C = \epsilon_r \epsilon_0 \frac{A}{d}$$

$$C_o = \epsilon_{ox} \frac{W (L_{drawn} - L_{effective}) / 2}{t_{ox}}$$

# Overlap Capacitance



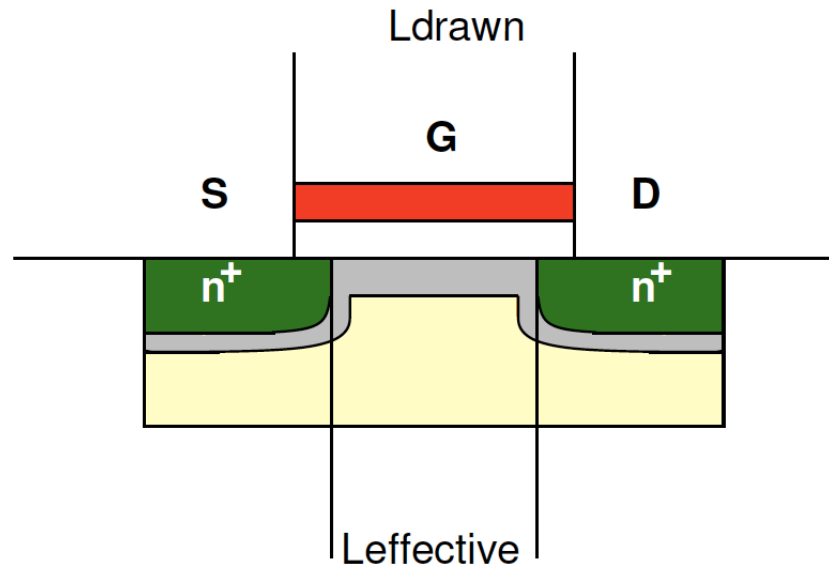
$$C = \epsilon_r \epsilon_0 \frac{A}{d}$$

$$C_{ox} = \frac{\epsilon_{ox}}{t_{ox}}$$

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$$C_o = \frac{1}{2} C_{ox} W (L_{drawn} - L_{effective})$$

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$$C_o = \frac{1}{2} C_{ox} W (L_{drawn} - L_{effective}) = C_{GSO} = C_{GDO}$$

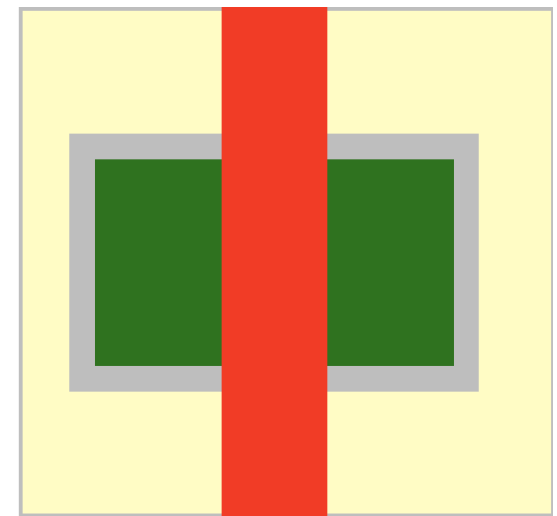
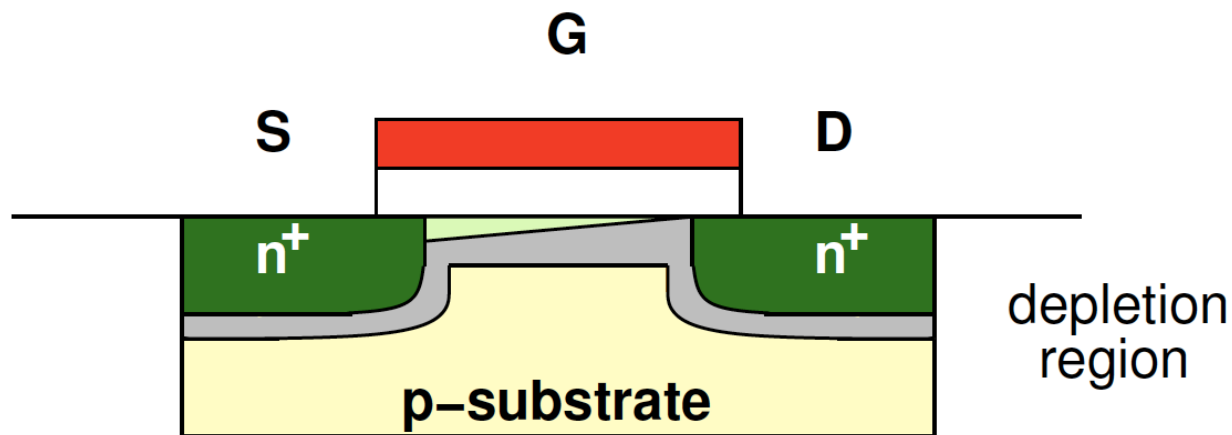
# Junction Capacitances

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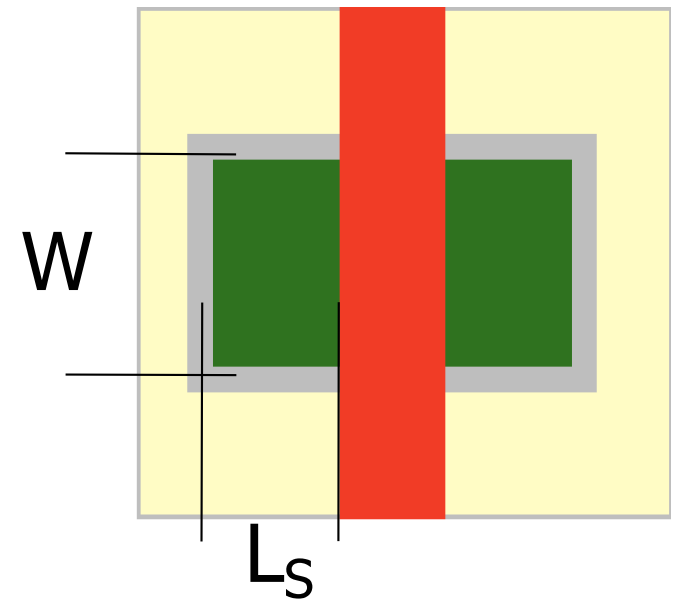
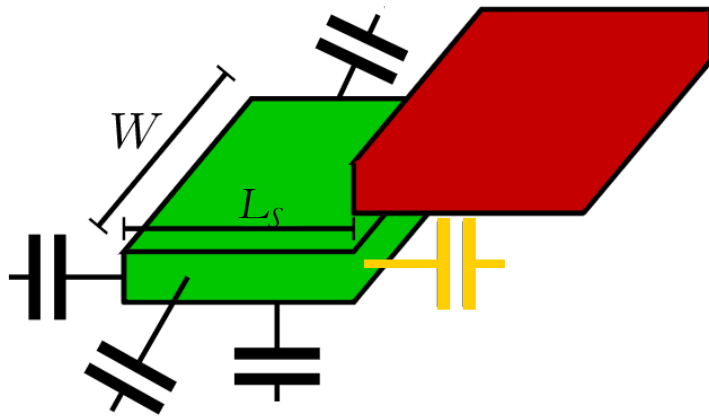
# Junction (diffusion) Capacitance

- ❑  $n^+$  contacts are formed by doping = diffusion
- ❑ Depletion under diffusion region (bottom-plate)
  - Due to reverse biased PN junction
  - Bottom-plate junction capacitance,  $C_j$
- ❑ Depletion around perimeter (sidewall) of diffusion region
  - Sidewall junction capacitance,  $C_{jsw}$



# Junction (Diffusion) Capacitance

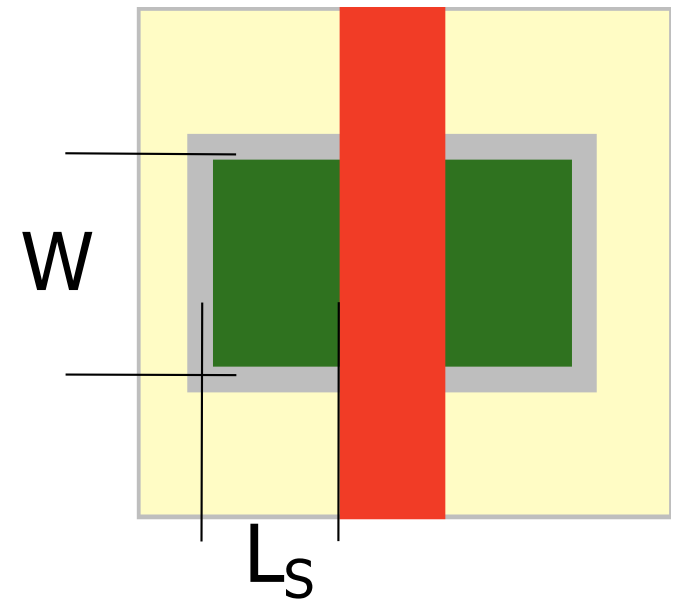
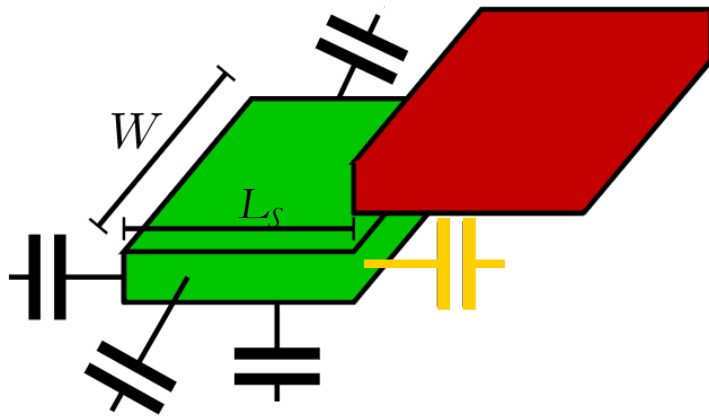
- ❑  $C_j$  – Bottom-plate junction capacitance (F/Area)
- ❑  $C_{jsw}$  – Sidewall junction capacitance (F/Length)
- ❑  $L_S$  – length of diffusion region



$$C_{diff} = C_j L_S W +$$

# Junction (Diffusion) Capacitance

- ❑  $C_j$  – Bottom-plate junction capacitance (F/Area)
- ❑  $C_{jsw}$  – Sidewall junction capacitance (F/Length)
- ❑  $L_S$  – length of diffusion region

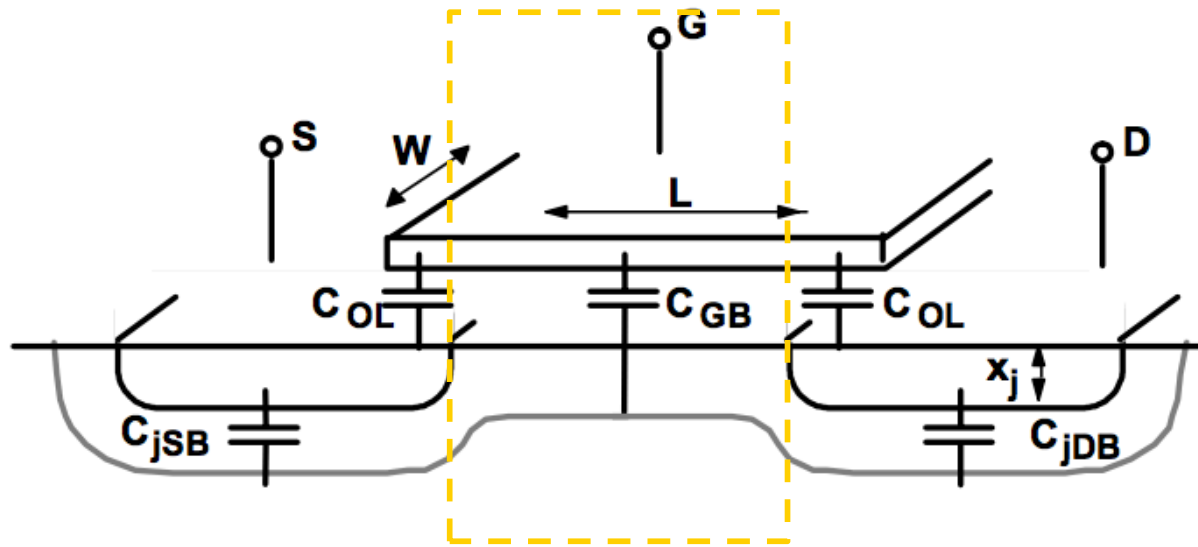


$$C_{diff} = C_j L_S W + C_{jsw} (2L_S + W)$$

# Gate-to-channel

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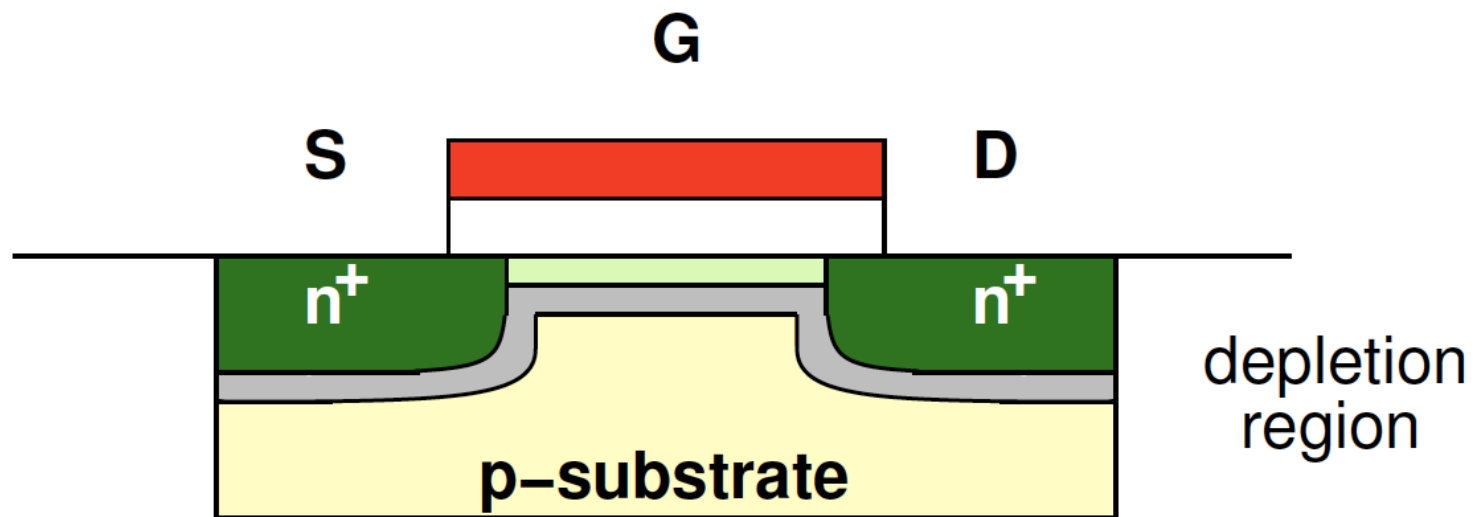
# MOSFET Parasitic Capacitance



- Any two conductors separated by an insulator form a parallel-plate capacitor
- Two types
  - **Extrinsic** – Outside the box (e.g. junction, overlap)
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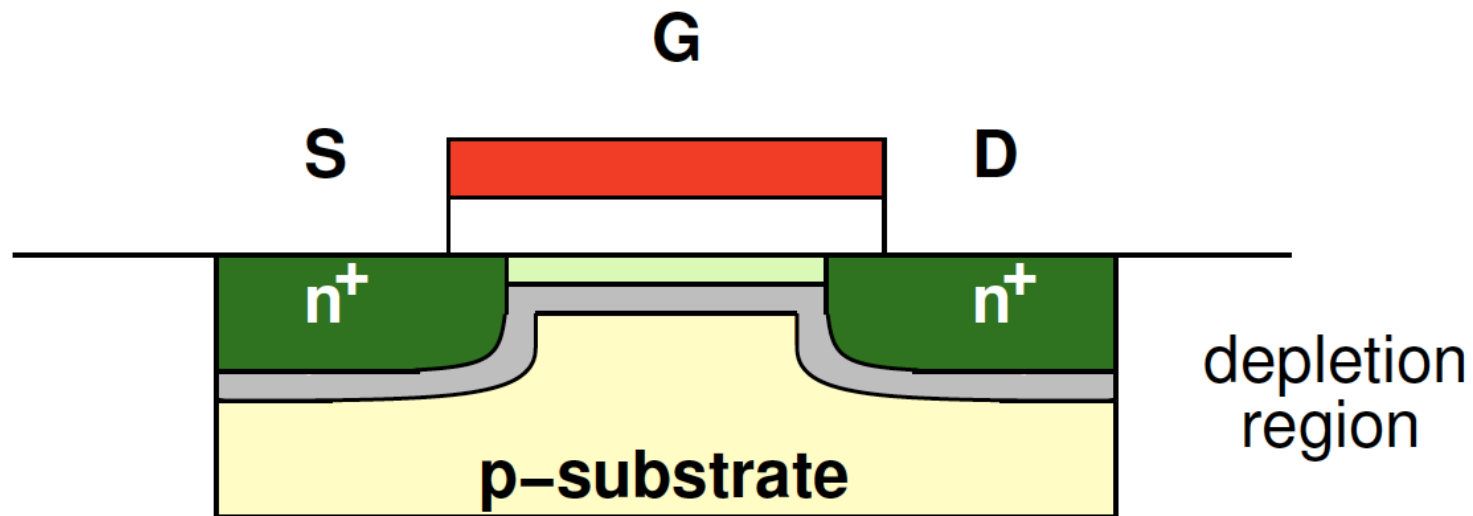
# Gate-to-Bulk Capacitance

- Looks like parallel plate capacitance
- Two components:
  - What is  $C_{GC}$ ? ( $C_{GCS}$ ,  $C_{GCD}$ )
  - What is  $C_{GCB}$ ?



# Gate-to-Channel Capacitance

- Looks like parallel plate capacitance
- Two components: **Case: Strong Inversion** (small  $V_{ds}$ )
  - $C_{GC}$
  - $C_{GCB}$



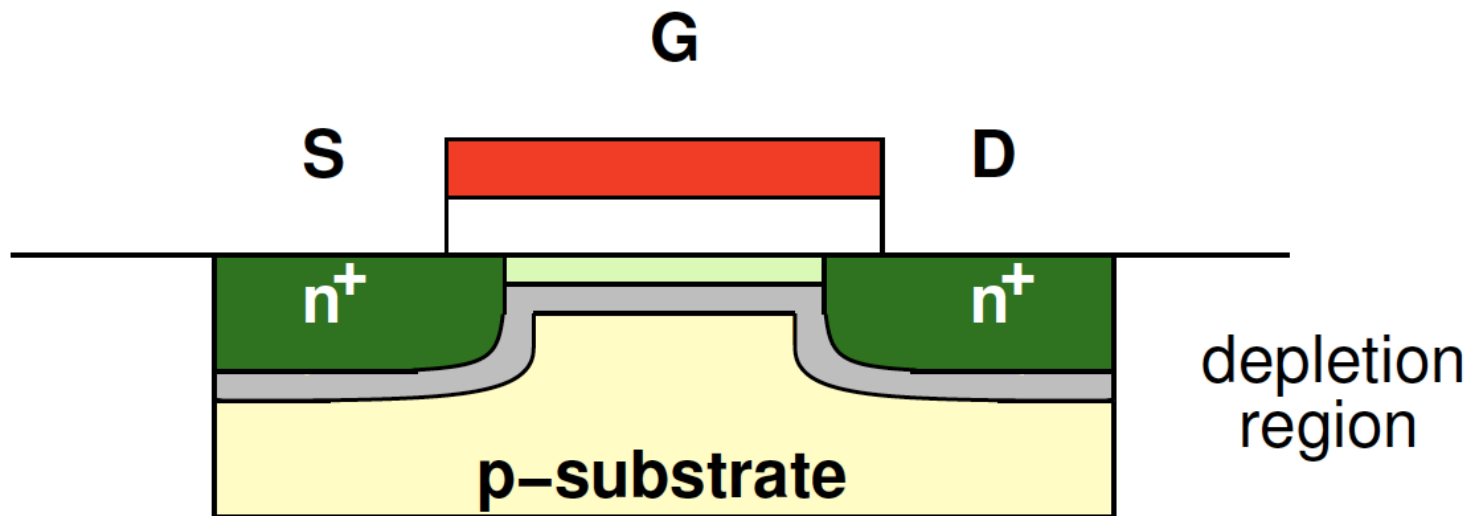
# Gate-to-Channel Capacitance

- Looks like parallel plate capacitance
- Two components: **Case: Strong Inversion**

- $C_{GC}$

- $C_{GCB}=0$

$$C_{GC} = C_{ox}WL_{effective}$$





# Gate-to-Channel Capacitance

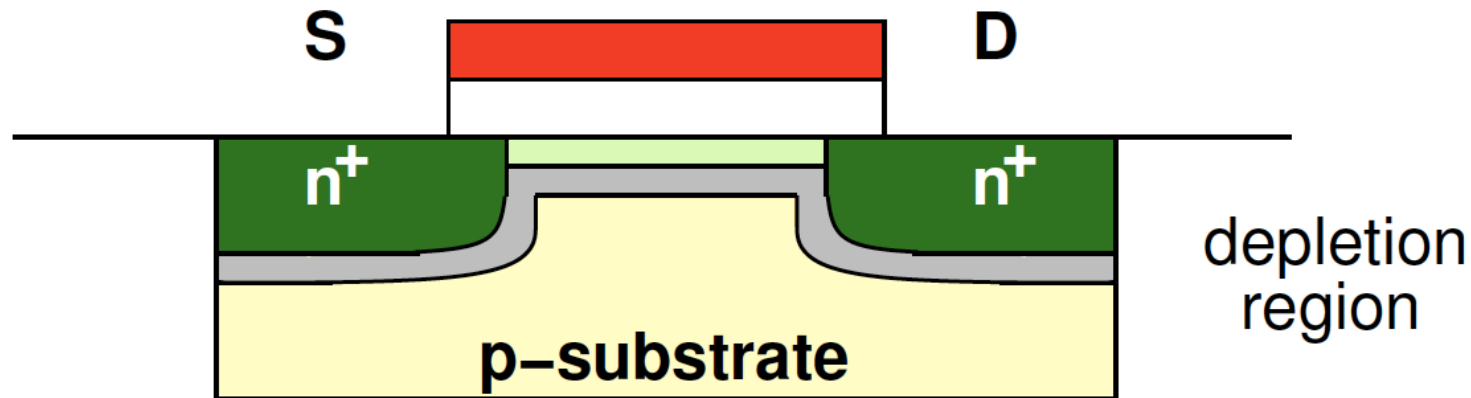
- Looks like parallel plate capacitance
- Two components: **Case: Strong Inversion**

- $C_{GC}$  – Split evenly between S and D

- $C_{GB} = 0$

$$C_{GC} = C_{ox} W L_{effective}$$

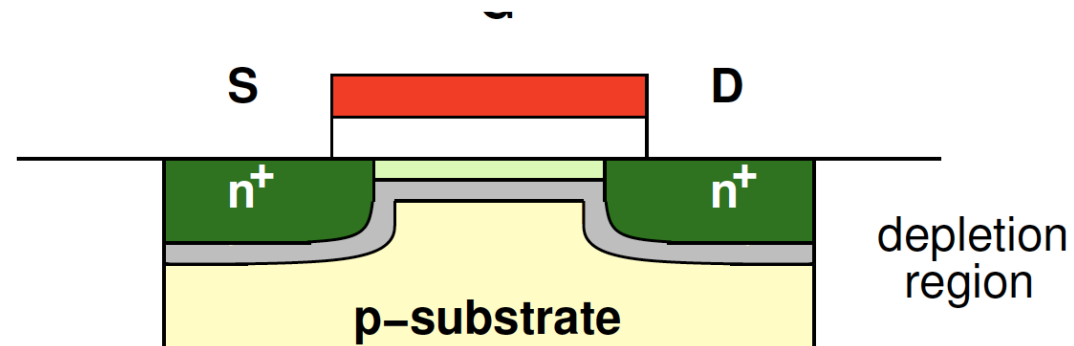
$$C_{GCS} = C_{GCD} = \frac{1}{2} C_{ox} W L_{effective}$$



# Gate-to-Source Capacitance

- Channel + Overlap

$$C_{GS} = C_{GCS} + C_{GSO}$$



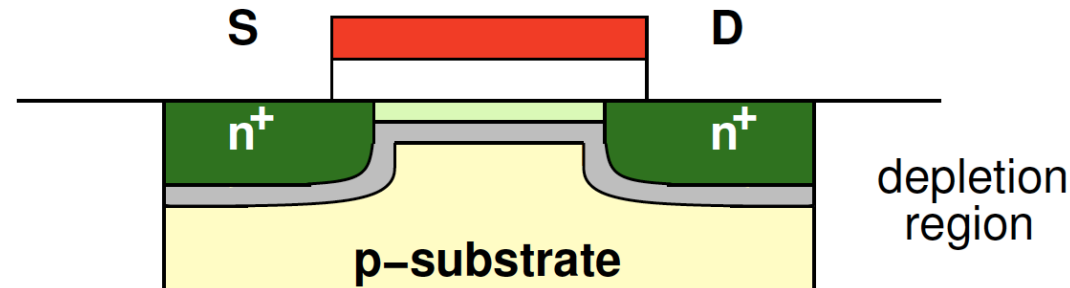
# Gate-to-Source Capacitance

- Channel + Overlap

$$C_{GS} = C_{GCS} + C_{GSO}$$

$$C_{GS} = \frac{1}{2} C_{OX} W (L_{drawn} - L_{effective}) + \frac{1}{2} C_{OX} W L_{effective}$$

$$C_{GS} = \frac{1}{2} C_{OX} W L_{drawn}$$



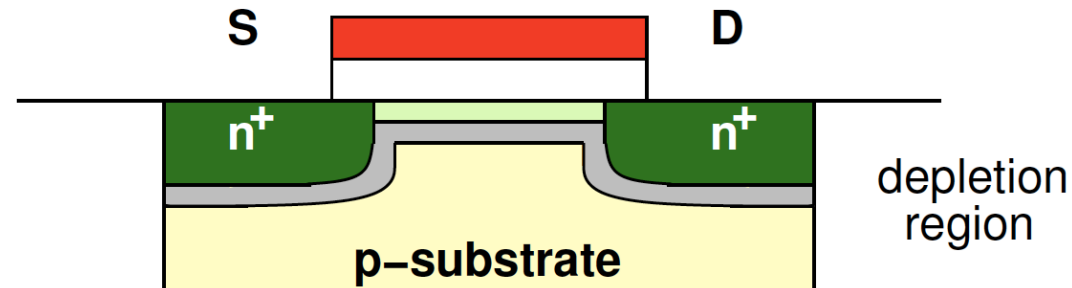
# Gate-to-Drain Capacitance

- Channel + Overlap

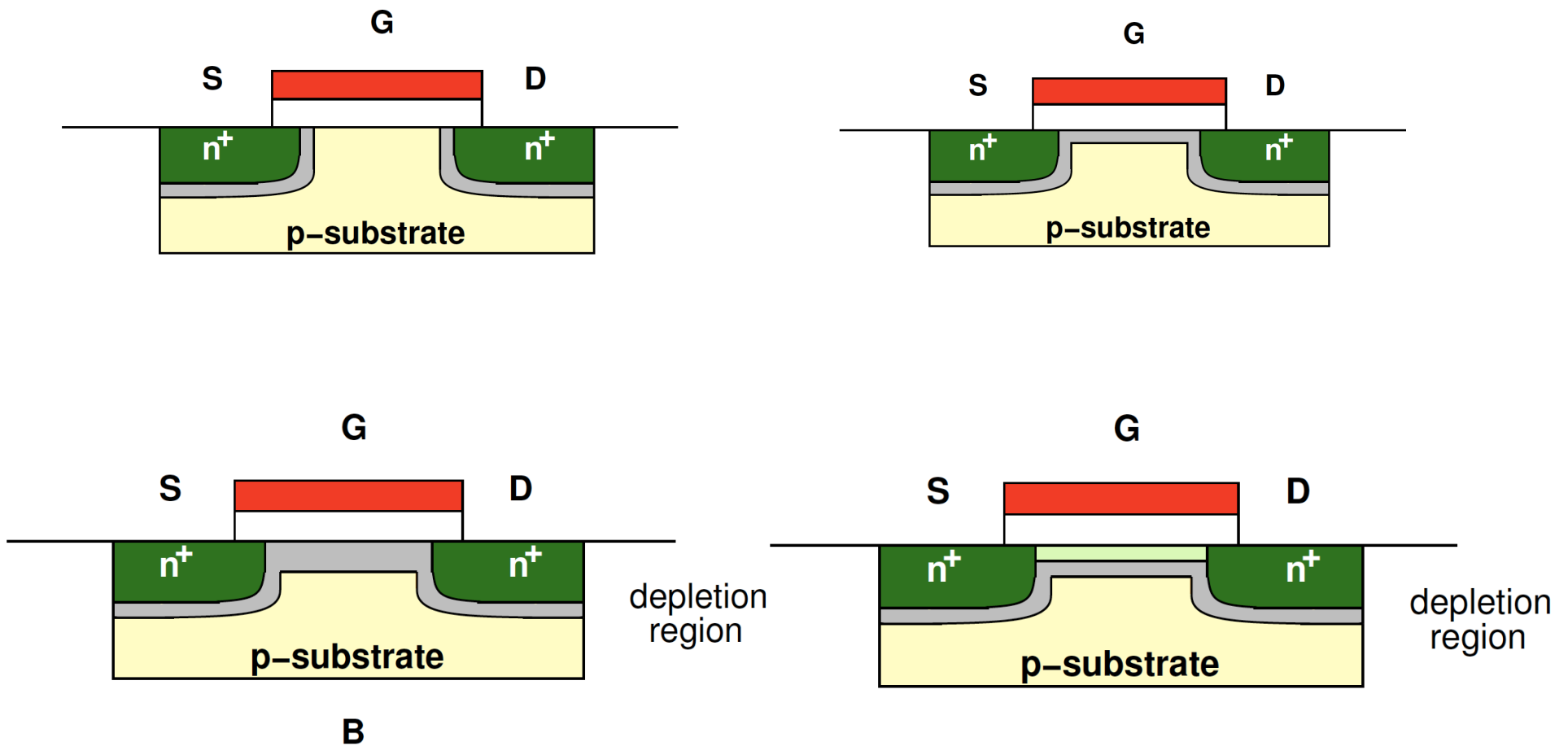
$$C_{GD} = C_{GCD} + C_{GDO}$$

$$C_{GD} = \frac{1}{2} C_{OX} W (L_{drawn} - L_{effective}) + \frac{1}{2} C_{OX} W L_{effective}$$

$$C_{GD} = \frac{1}{2} C_{OX} W L_{drawn}$$

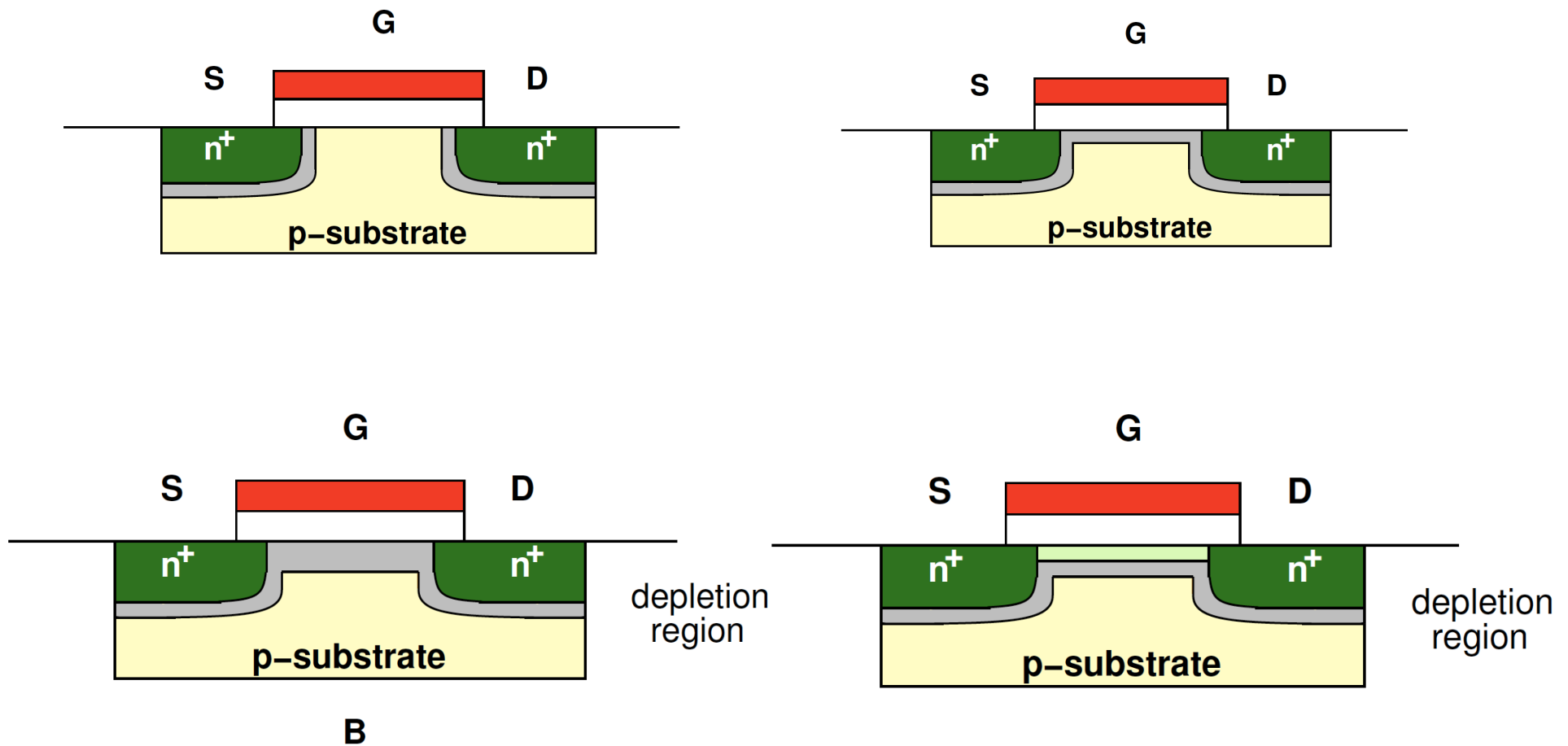


# Channel Evolution: Weak Inversion



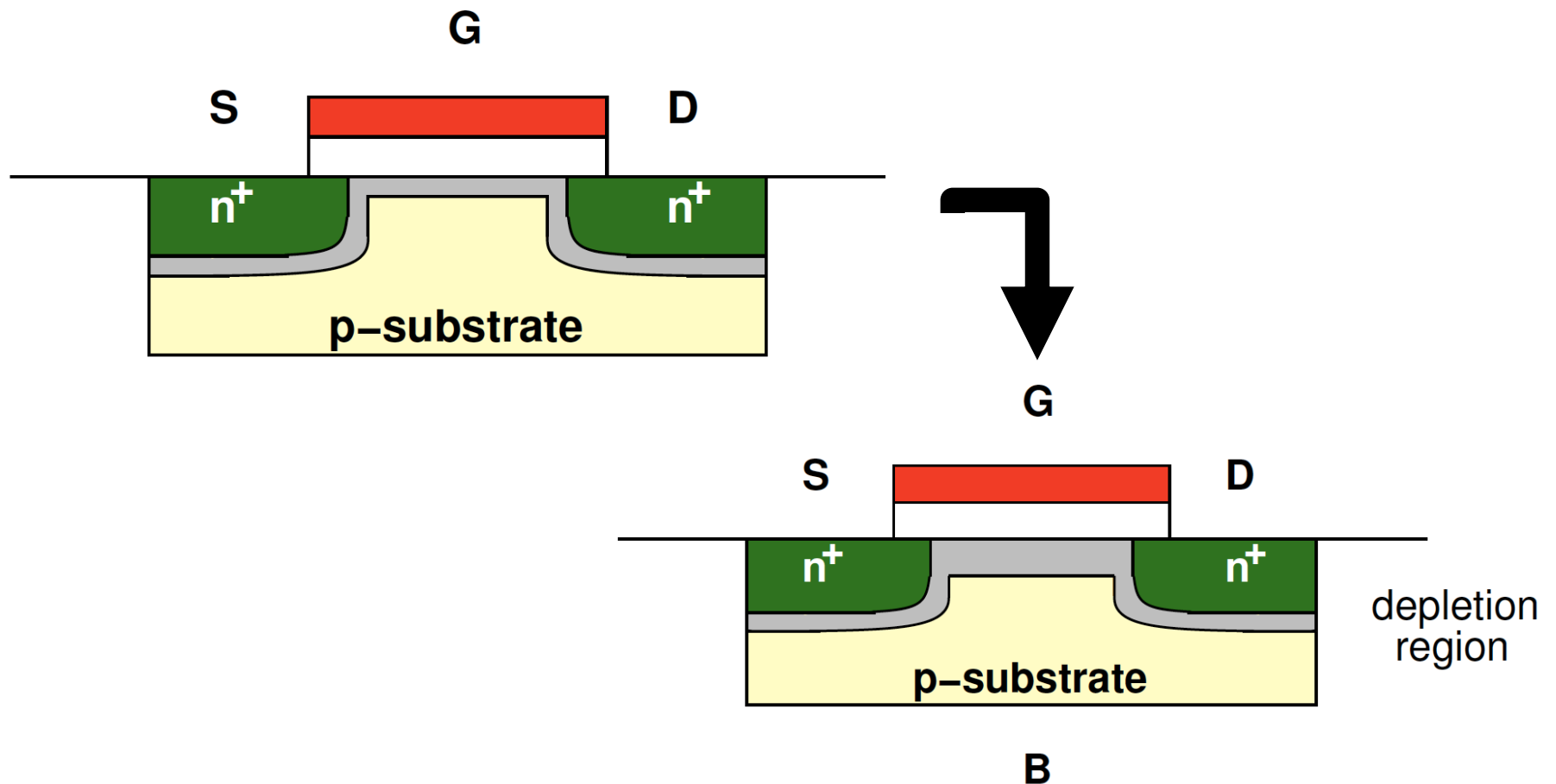
# Channel Evolution: Weak Inversion

□  $V_{GS} = 0 \rightarrow C_{GC} = 0, C_{GCB} = WLC_{ox}$



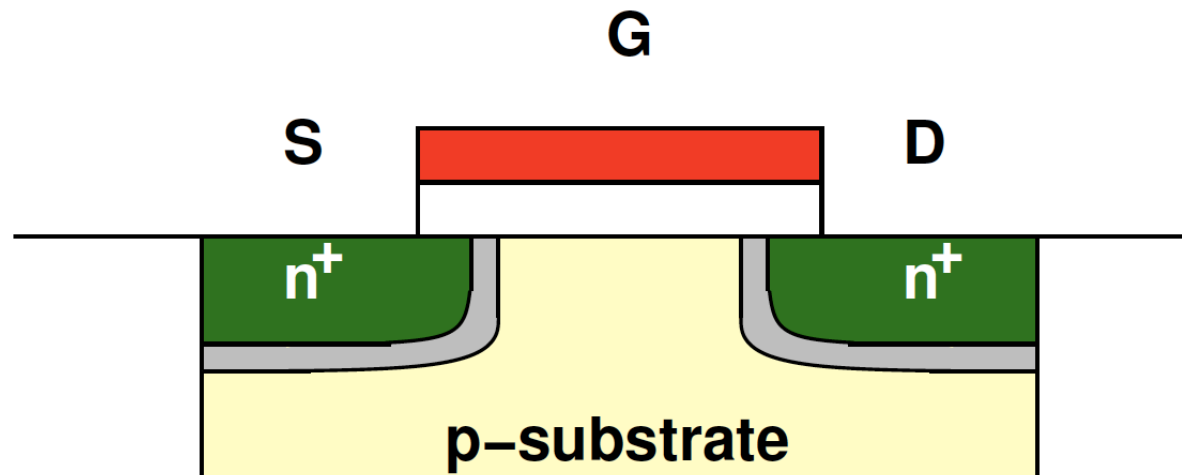
# Channel Evolution: Weak Inversion

- What happens to capacitance here as  $V_{GS}$  increases?
  - Capacitor plate distance?



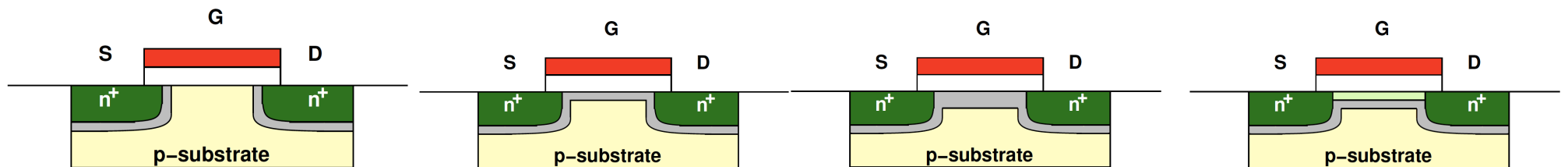
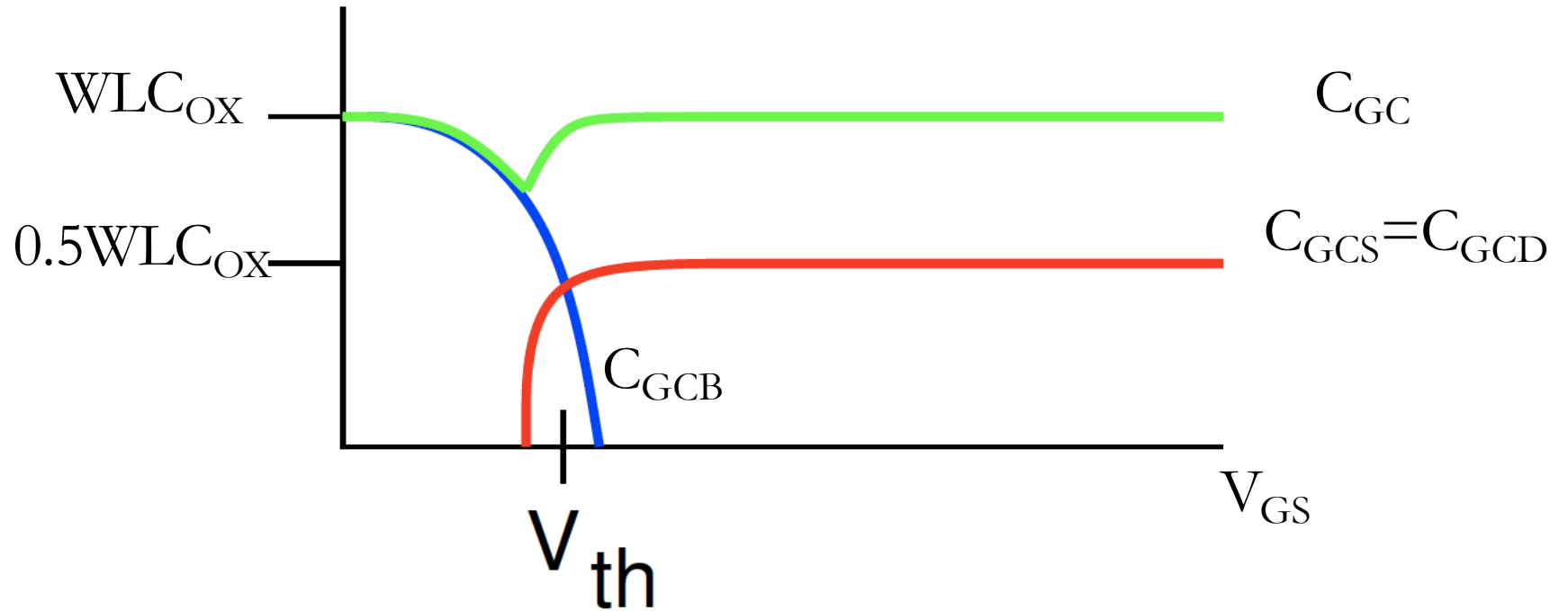
# Channel Evolution: Weak Inversion

- ❑ Capacitance is initially dominated by Gate-to-bulk capacitance ( $C_{GCS,D}=0$ )
- ❑ Gate-to-bulk capacitance drops as  $V_{GS}$  increases toward  $V_{th}$





# Capacitance vs $V_{GS}$ ( $V_{DS}=0$ )

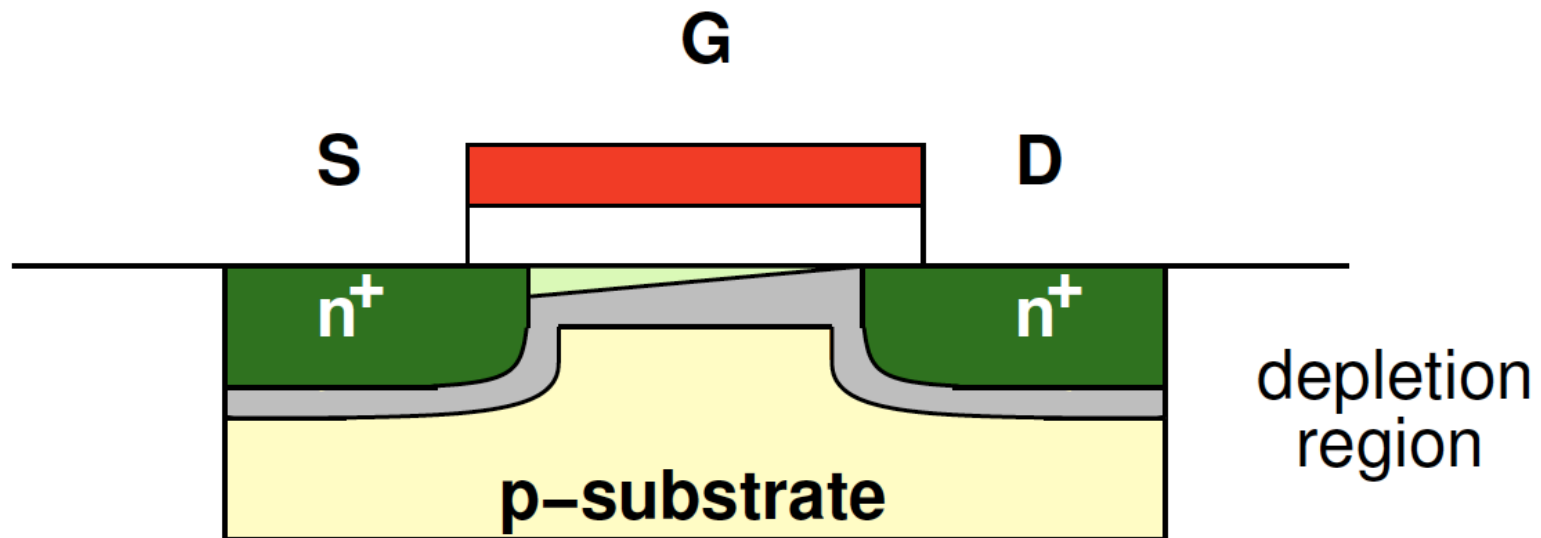


Increasing  $V_{GS}$   $\longrightarrow$



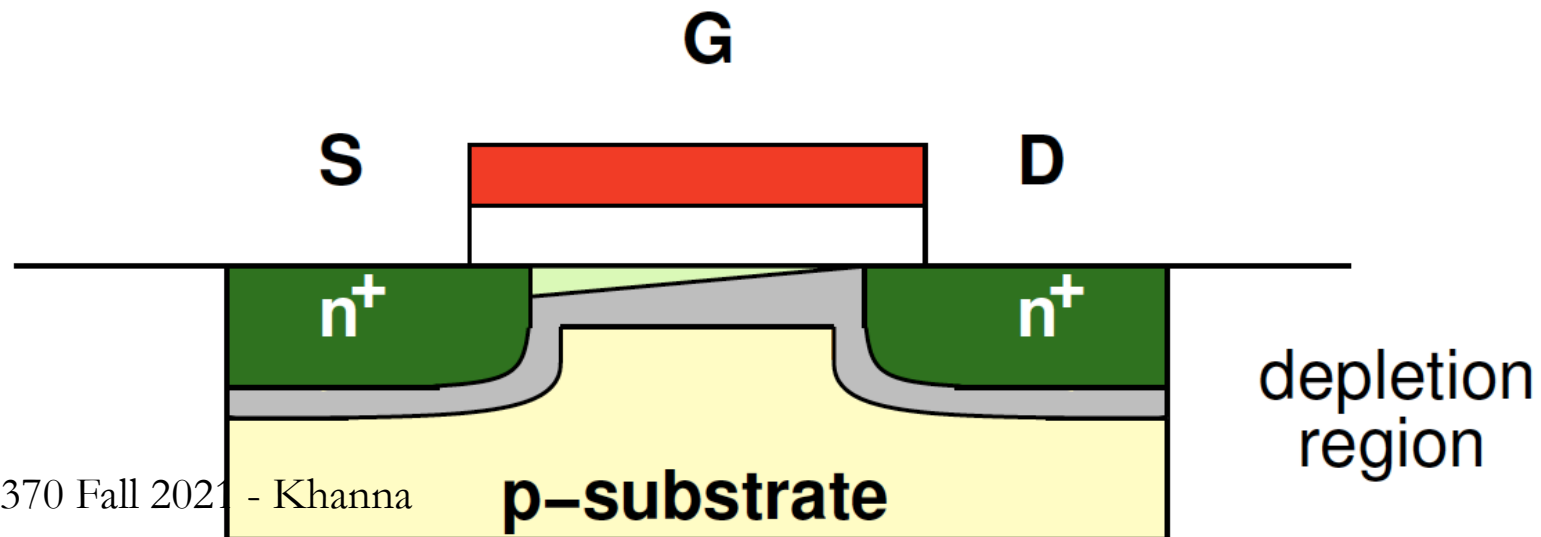
# Saturation Capacitance?

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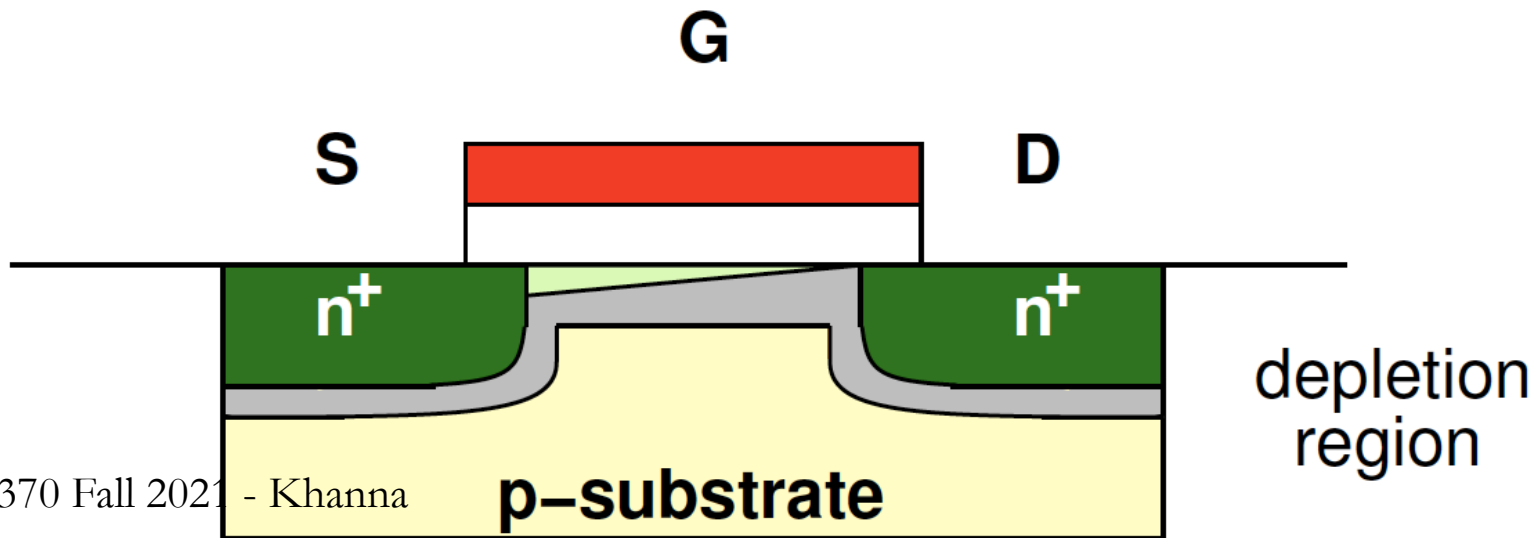
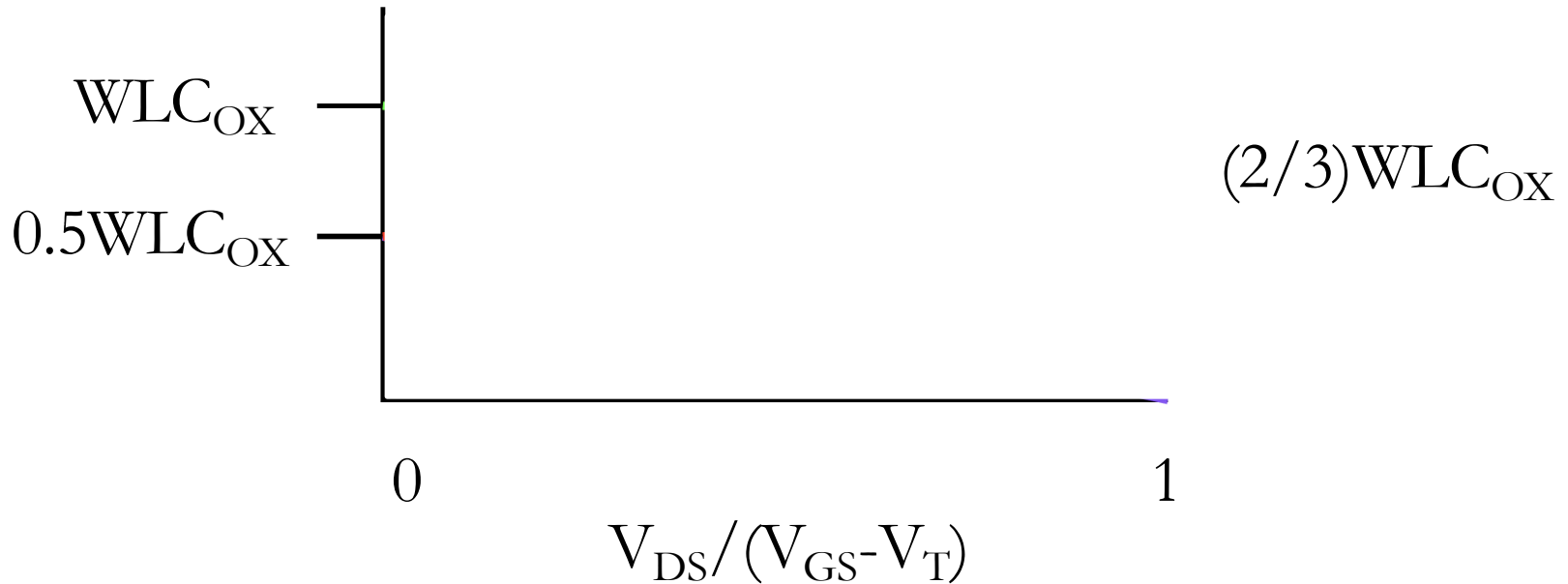


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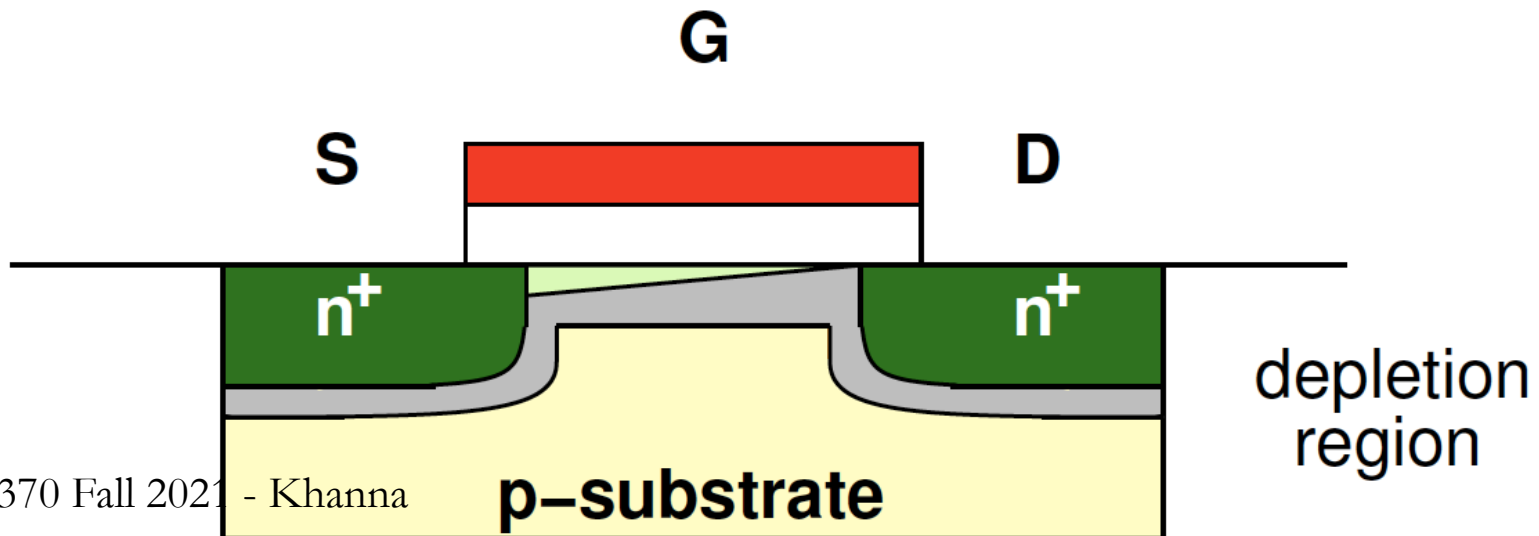
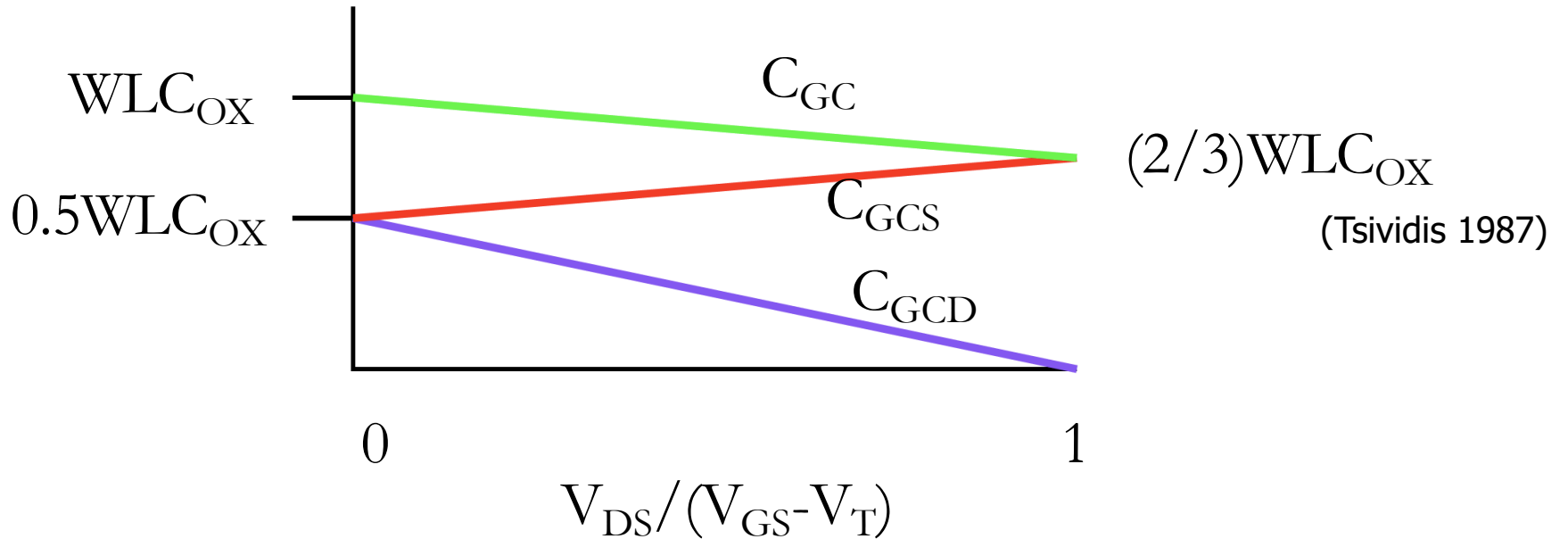
- ❑ Source end of channel in inversion
- ❑ Voltage at drain end of channel at or below threshold
- ❑ Capacitance shifts to source
  - Total capacitance reduced



# Saturation Capacitance

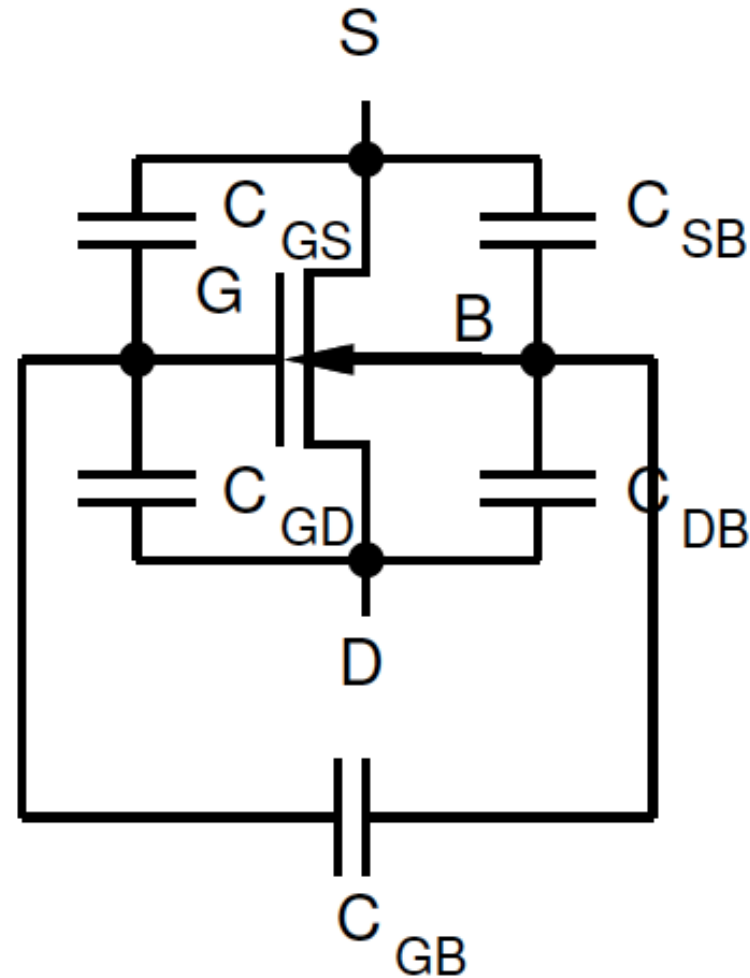


# Saturation Capacitance



# Capacitance Roundup

- $C_{GS} = C_{GCS} + C_{GSO}$
- $C_{GD} = C_{GCD} + C_{GDO}$
- $C_{GB} = C_{GCB}$
- $C_{SB} = C_{diff}$
- $C_{DB} = C_{diff}$





# First Order Capacitance Summary

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Operation Region	$C_{GCB}$	$C_{GCS}$	$C_{GCD}$	$C_{GC}$	$C_G$
Subthreshold					
Linear					
Saturation					

# First Order Capacitance Summary

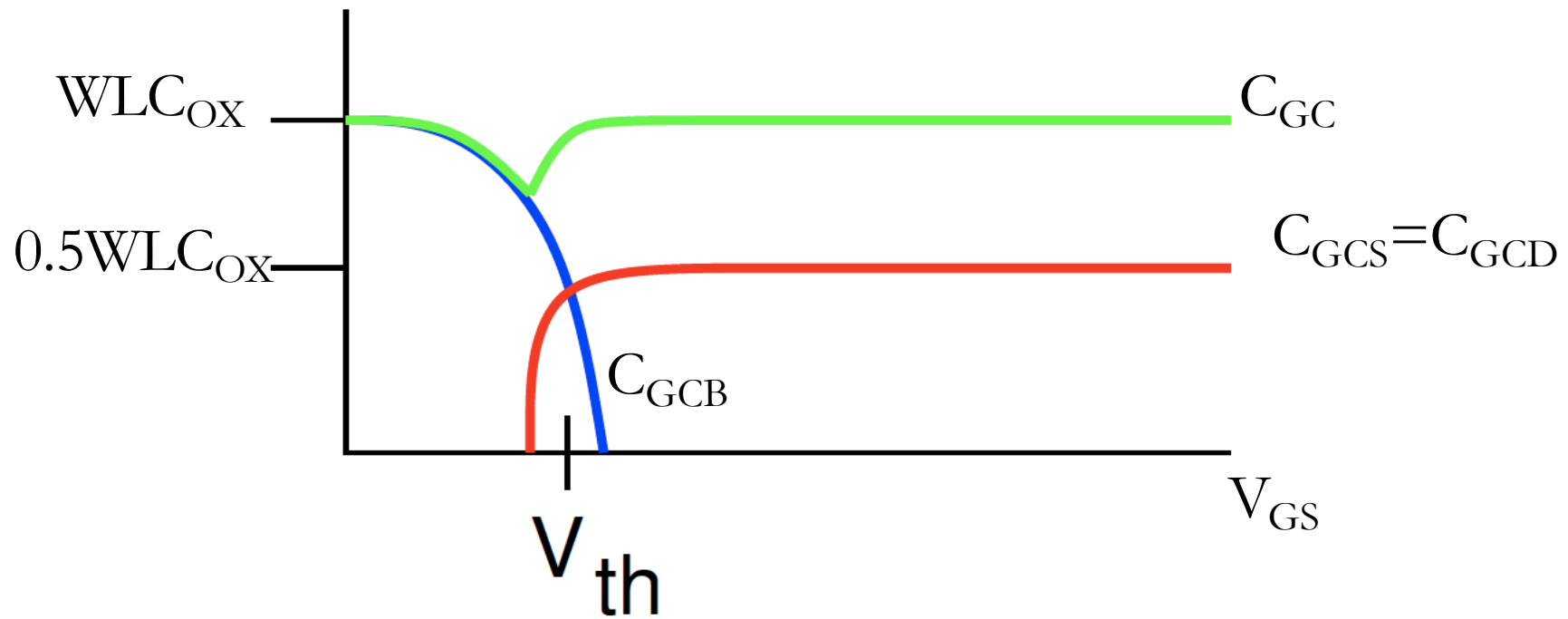
Operation Region	$C_{GCB}$	$C_{GCS}$	$C_{GCD}$	$C_{GC}$	$C_G$
Subthreshold					
Linear	0	$C_{OX}WL/2$	$C_{OX}WL/2$		
Saturation					

$$C_{GCS} = C_{GCD} = \frac{1}{2} C_{ox} WL_{effective}$$



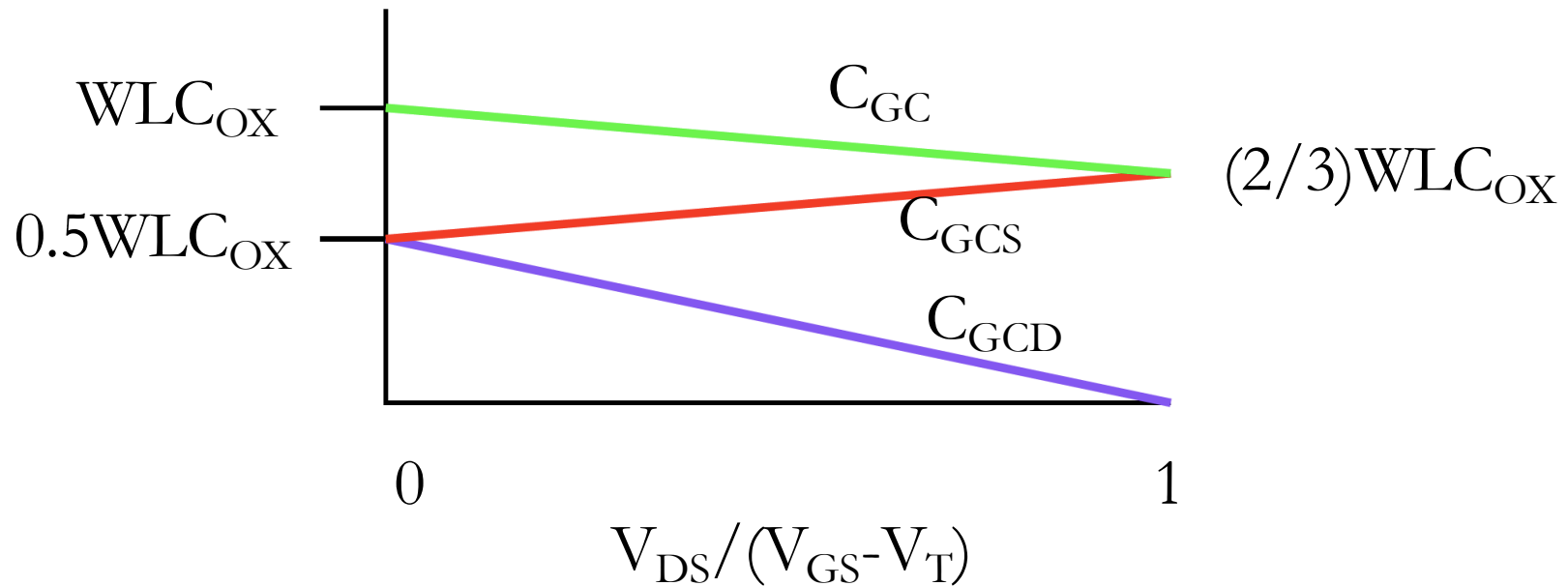
# First Order Capacitance Summary

Operation Region	$C_{GCB}$	$C_{GCS}$	$C_{GCD}$	$C_{GC}$	$C_G$
Subthreshold	$C_{OX}WL$	0	0		
Linear	0	$C_{OX}WL/2$	$C_{OX}WL/2$		
Saturation					



# First Order Capacitance Summary

Operation Region	$C_{GCB}$	$C_{GCS}$	$C_{GCD}$	$C_{GC}$	$C_G$
Subthreshold	$C_{OX}WL$	0	0		
Linear	0	$C_{OX}WL/2$	$C_{OX}WL/2$		
Saturation	0	$(2/3)C_{OX}WL$	0		





# First Order Capacitance Summary

Operation Region	$C_{GCB}$	+	$C_{GCS}$	+	$C_{GCD}$	=	$C_{GC}$	$C_G$
Subthreshold	$C_{OX}WL$		0		0		$C_{OX}WL$	
Linear	0		$C_{OX}WL/2$		$C_{OX}WL/2$		$C_{OX}WL$	
Saturation	0		$(2/3)C_{OX}WL$		0		$(2/3)C_{OX}WL$	

# First Order Capacitance Summary

Operation Region	$C_{GCB}$	$C_{GCS}$	$C_{GCD}$	$C_{GC}$	$C_G$
Subthreshold	$C_{OX}WL$	0	0	$C_{OX}WL$	$C_{OX}WL+2C_O$
Linear	0	$C_{OX}WL/2$	$C_{OX}WL/2$	$C_{OX}WL$	$C_{OX}WL+2C_O$
Saturation	0	$(2/3)C_{OX}WL$	0	$(2/3)C_{OX}WL$	$(2/3)C_{OX}WL+2C_O$

$$C_o = \frac{1}{2} C_{ox} W (L_{drawn} - L_{effective}) = C_{GSO} = C_{GDO}$$

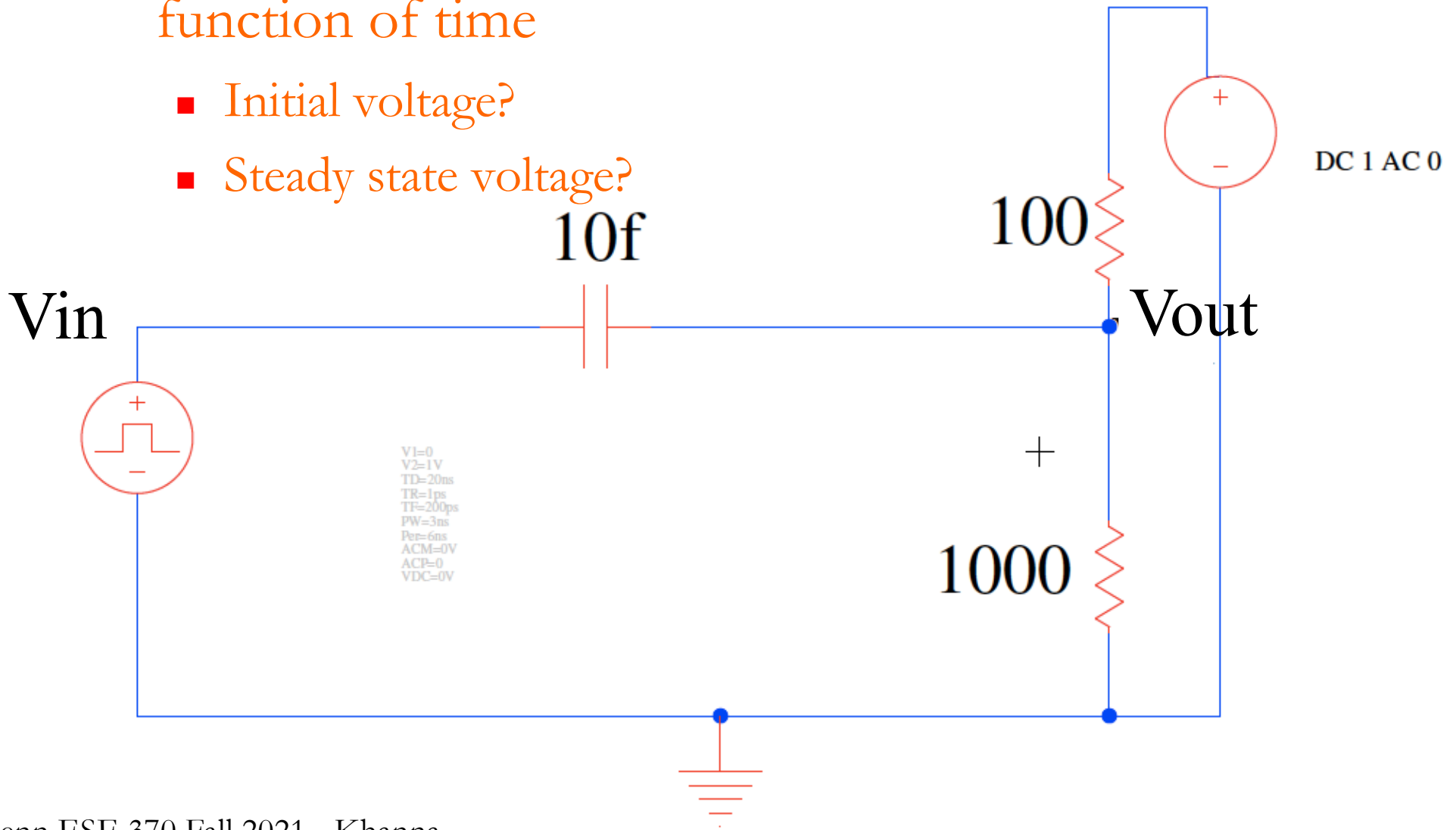
# One Implication

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Feedback Capacitance  $C_{gd}$

# Step Response? (Preclass 2)

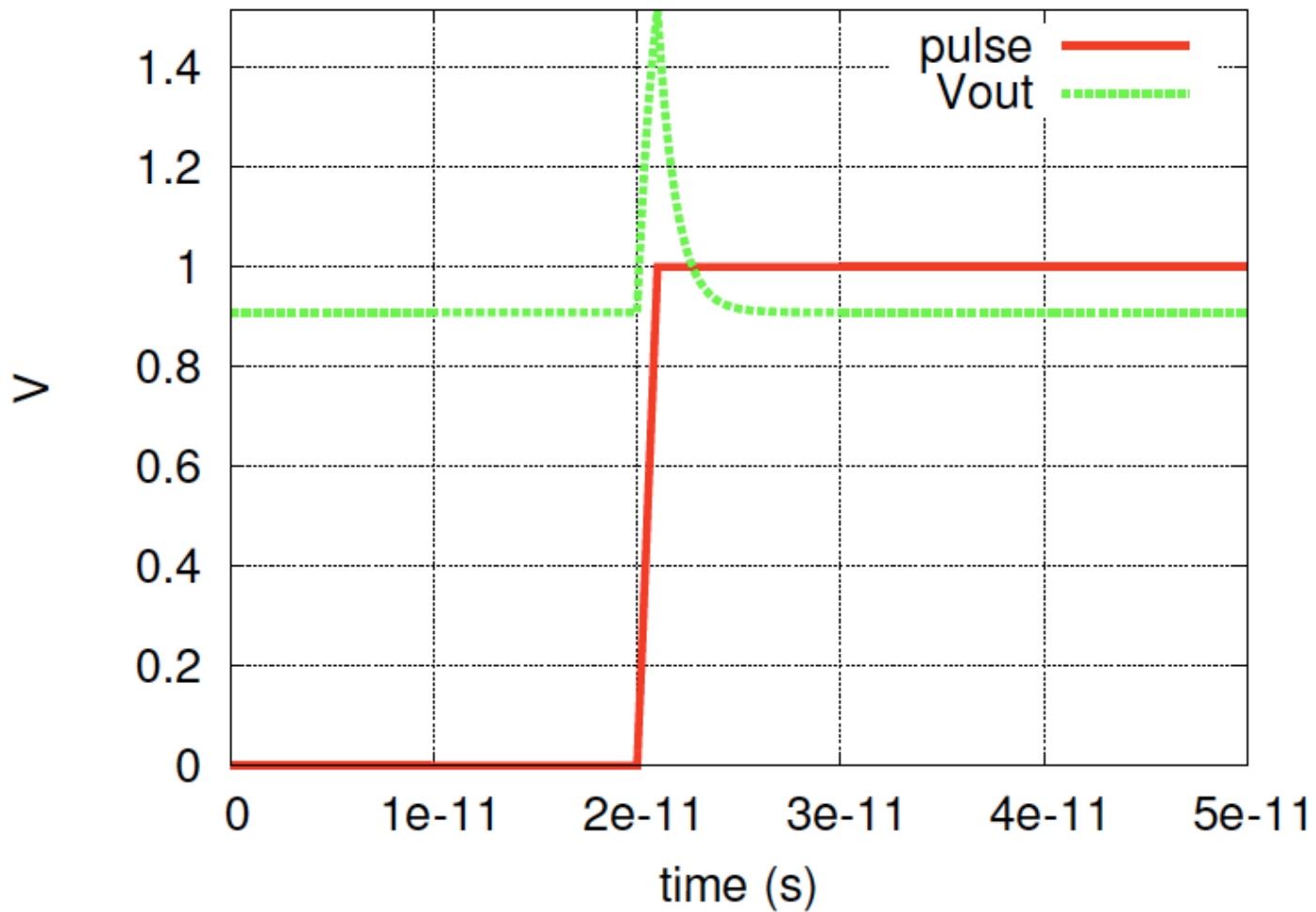
- $V_{in}$  steps from 0 to 1, what does  $V_{out}$  look like as a function of time
  - Initial voltage?
  - Steady state voltage?





# Step Response

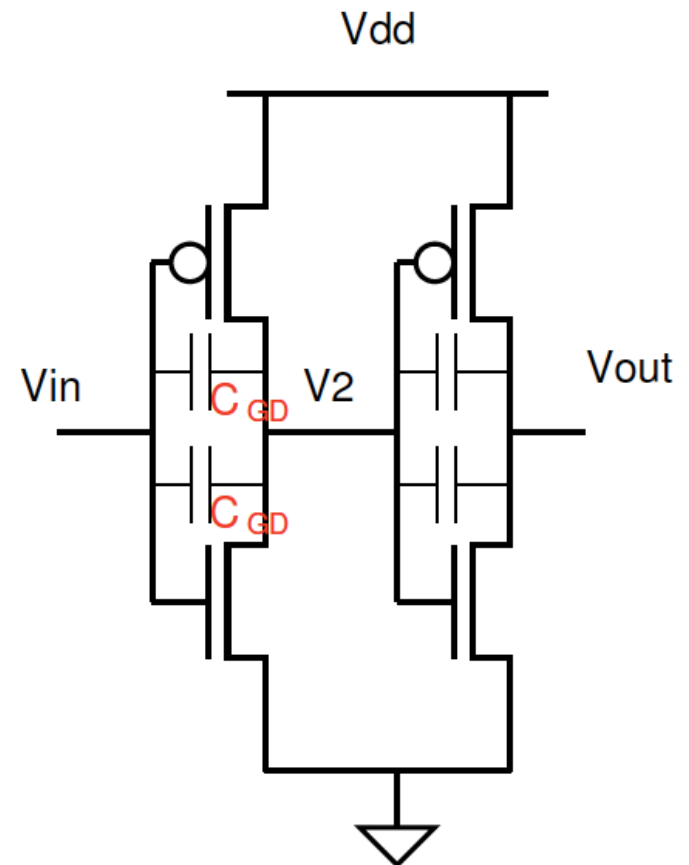
Voltage peaking!



# Impact of $C_{GD}$

□ What does  $C_{GD}$  do to the switching response here?

- $V_2$
- $V_{out}$

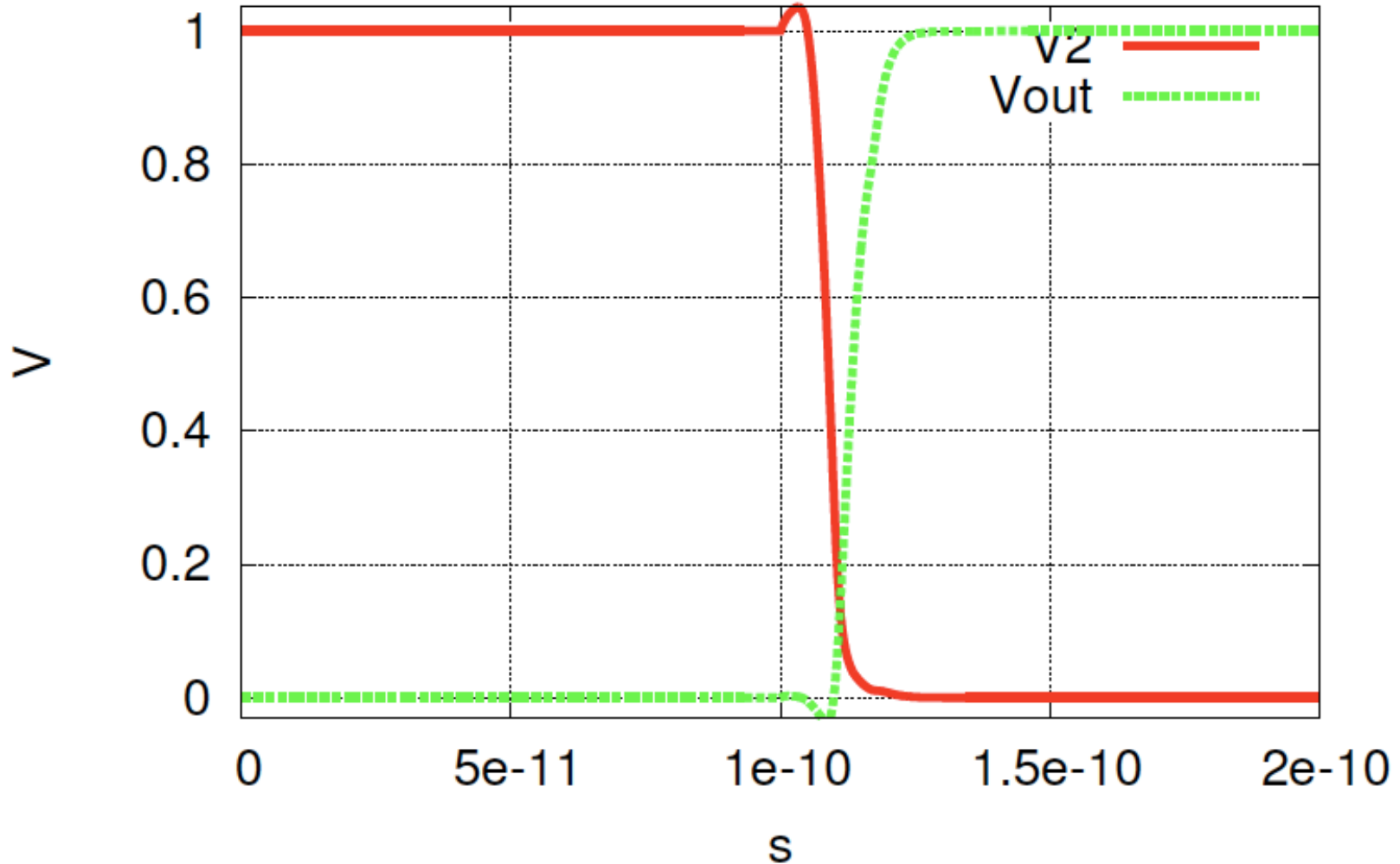






# Impact of $C_{GD}$

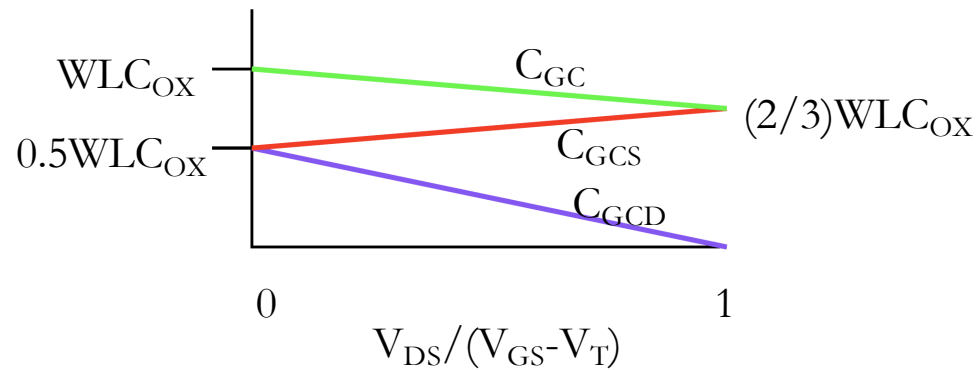
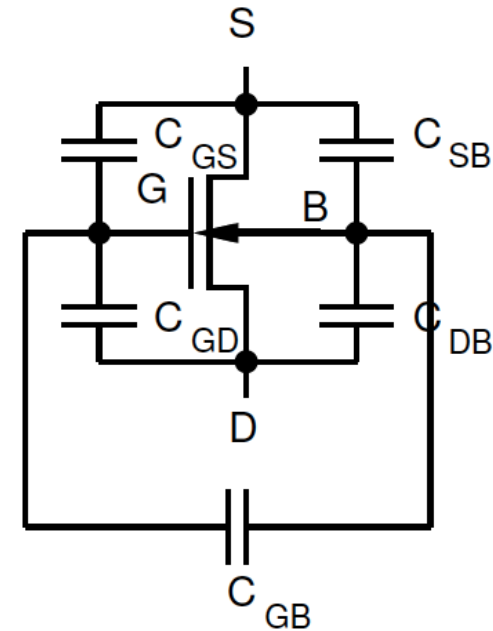
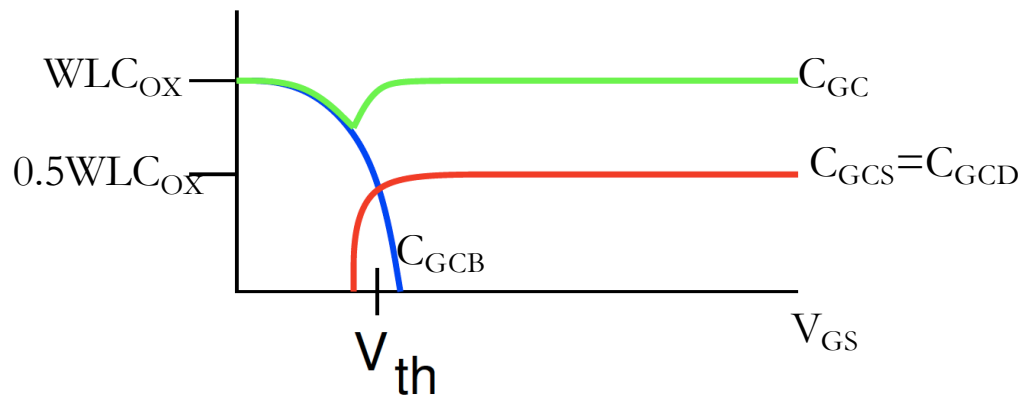
\*\*\* spice deck for cell flat\_inv{sch} from library test



# Big Idea

## Capacitance

- To every terminal
- Voltage dependent






# Admin

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- HW 3
  - Due Monday
- Midterm 1 Friday 10/1 (next week)
  - 7-9pm in Towne 309
  - No Lecture, virtual office hours
  - Midterms from 2010-2019 (and Project 1 from 2020)
    - All online with and without answers
  - Midterm 1 Review virtual session next week
    - See Piazza for poll coming soon
  - Conflicts must let me know *ASAP*



# Midterm 1 - Content

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## □ Lec 1 - 9

- Identify CMOS/non-CMOS
- Identify CMOS function
- Any logic function → CMOS gate
- Noise Margins / Restoration
- Circuit first order switching rise/fall times
  - Output equivalent resistance
  - Load capacitance
- MOS Model
- Identify transistor region of operation
- Analysis with transistor IV models
- MOS capacitance models